



## FEATURES:

- **Flash Organization: 2M x16 or 4M x8**
- **Dual-Bank Architecture for Concurrent Read/Write Operation**
  - 32 Mbit Top Sector Protection
  - SST34HF32x4: 8 Mbit + 24Mbit
  - SST34HF3282: 4 Mbit + 28 Mbit
- **PSRAM Organization:**
  - 4 Mbit: 256K x16
  - 8 Mbit: 512K x16
- **Single 2.7-3.3V Read and Write Operations**
- **Superior Reliability**
  - Endurance: 100,000 Cycles (typical)
  - Greater than 100 years Data Retention
- **Low Power Consumption:**
  - Active Current: 25 mA (typical)
  - Standby Current: 20  $\mu$ A (typical)
- **Hardware Sector Protection (WP#)**
  - Protects 8 KWord in the smaller bank by holding WP# low and unprotects by holding WP# high
- **Hardware Reset Pin (RST#)**
  - Resets the internal state machine to reading data array
- **Byte Selection for Flash (CIOF pin)**
  - Selects 8-bit or 16-bit mode
- **Sector-Erase Capability**
  - Uniform 2 KWord sectors
- **Flash Chip-Erase Capability**
- **Block-Erase Capability**
  - Uniform 32 KWord blocks
- **Erase-Suspend / Erase-Resume Capabilities**
- **Read Access Time**
  - Flash: 70 ns
  - PSRAM: 70 ns
- **Security ID Feature**
  - SST: 128 bits
  - User: 256 Bytes
- **Latched Address and Data**
- **Fast Erase and Program (typical):**
  - Sector-Erase Time: 18 ms
  - Block-Erase Time: 18 ms
  - Chip-Erase Time: 35 ms
  - Program Time: 7  $\mu$ s
- **Automatic Write Timing**
  - Internal V<sub>PP</sub> Generation
- **End-of-Write Detection**
  - Toggle Bit
  - Data# Polling
  - Ready/Busy# pin
- **CMOS I/O Compatibility**
- **JEDEC Standard Command Set**
- **Packages Available**
  - 56-ball LFBGA (8mm x 10mm)
  - 62-ball LFBGA (8mm x 10mm)
- **All non-Pb (lead-free) devices are RoHS compliant**

## PRODUCT DESCRIPTION

The SST34HF3244, SST34HF3282, and SST34HF3284 ComboMemory devices integrate either a 2M x16 or 4M x8 CMOS flash memory bank with either a 256K x16 or 512K x16 CMOS pseudo SRAM (PSRAM) memory bank in a multi-chip package (MCP). These devices are fabricated using SST's proprietary, high-performance CMOS SuperFlash technology incorporating the split-gate cell design and thick-oxide tunneling injector to attain better reliability and manufacturability compared with alternate approaches. The SST34HF32xx devices are ideal for applications such as cellular phones, GPS devices, PDAs, and other portable electronic devices in a low power and small form factor system.

The SST34HF32xx feature dual flash memory bank architecture allowing for concurrent operations between the two flash memory banks and the PSRAM. The devices can read data from either bank while an Erase or Program operation is in progress in the opposite bank. The two flash

memory banks are partitioned into 4 Mbit + 28 Mbit or 8 Mbit + 24 Mbit with top sector protection options for storing boot code, program code, configuration/parameter data and user data.

The SuperFlash technology provides fixed Erase and Program times, independent of the number of Erase/Program cycles that have occurred. Therefore, the system software or hardware does not have to be modified or de-rated as is necessary with alternative flash technologies, whose Erase and Program times increase with accumulated Erase/Program cycles. The SST34HF32xx devices offer a guaranteed endurance of 10,000 cycles. Data retention is rated at greater than 100 years. With high-performance Program operations, the flash memory banks provide a typical Program time of 7  $\mu$ sec. The entire flash memory bank can be erased and programmed word-by-word in typically 4 seconds for the SST34HF32xx, when using interface features such as Toggle Bit, Data# Polling, or RY/BY# to indicate the



## 32 Mbit Concurrent SuperFlash + 4/8 Mbit PSRAM ComboMemory SST34HF3244 / SST34HF3282 / SST34HF3284

### Data Sheet

completion of Program operation. To protect against inadvertent flash write, the SST34HF32xx devices contain on-chip hardware and software data protection schemes.

The flash and PSRAM operate as two independent memory banks with respective bank enable signals. The memory bank selection is done by two bank enable signals. The PSRAM bank enable signals, BES1# and BES2, select the PSRAM bank. The flash memory bank enable signal, BEF#, has to be used with Software Data Protection (SDP) command sequence when controlling the Erase and Program operations in the flash memory bank. The memory banks are superimposed in the same memory address space where they share common address lines, data lines, WE# and OE# which minimize power consumption and area.

Designed, manufactured, and tested for applications requiring low power and small form factor, the SST34HF32xx are offered in both commercial and extended temperatures and a small footprint package to meet board space constraint requirements. See Figures 2 and 3 for pin assignments.

### Device Operation

The SST34HF32xx uses BES1#, BES2 and BEF# to control operation of either the flash or the PSRAM memory bank. When BEF# is low, the flash bank is activated for Read, Program or Erase operation. When BES1# is low, and BES2 is high the PSRAM is activated for Read and Write operation. BEF# and BES1# cannot be at low level, and BES2 cannot be at high level at the same time. **If all bank enable signals are asserted, bus contention will result and the device may suffer permanent damage.** All address, data, and control lines are shared by flash and PSRAM memory banks which minimizes power consumption and loading. The device goes into standby when BEF# and BES1# bank enables are raised to  $V_{IHC}$  (Logic High) or when BEF# is high and BES2 is low.

### Concurrent Read/Write Operation

Dual bank architecture of SST34HF32xx devices allows the Concurrent Read/Write operation whereby the user can read from one bank while programming or erasing in the other bank. This operation can be used when the user needs to read system code in one bank while updating data in the other bank. See Table 3 for dual-bank memory organization.

#### CONCURRENT READ/WRITE STATES

Flash		PSRAM
Bank 1	Bank 2	
Read	Write	No Operation
Write	Read	No Operation
Write	No Operation	Read
No Operation	Write	Read
Write	No Operation	Write
No Operation	Write	Write

**Note:** For the purposes of this table, write means to perform Block-/Sector-Erase or Program operations as applicable to the appropriate bank.

### Flash Read Operation

The Read operation of the SST34HF32xx is controlled by BEF# and OE#, both have to be low for the system to obtain data from the outputs. BEF# is used for device selection. When BEF# is high, the chip is deselected and only standby power is consumed. OE# is the output control and is used to gate data from the output pins. The data bus is in high impedance state when either BEF# or OE# is high. Refer to Figure 7, the Read cycle timing diagram, for further details.



## Flash Program Operation

These devices are programmed on a word-by-word or byte-by-byte basis depending on the state of the CIOF pin. Before programming, one must ensure that the sector being programmed is fully erased.

The Program operation is accomplished in three steps:

1. Software Data Protection is initiated using the three-byte load sequence.
2. Address and data are loaded.

During the Program operation, the addresses are latched on the falling edge of either BEF# or WE#, whichever occurs last. The data is latched on the rising edge of either BEF# or WE#, whichever occurs first.

3. The internal Program operation is initiated after the rising edge of the fourth WE# or BEF#, whichever occurs first. The Program operation, once initiated, will be completed typically within 7  $\mu$ s.

See Figures 8 and 9 for WE# and BEF# controlled Program operation timing diagrams and Figure 22 for flowcharts. During the Program operation, the only valid reads are Data# Polling and Toggle Bit. During the internal Program operation, the host is free to perform additional tasks. Any commands issued during an internal Program operation are ignored.

## Flash Sector- /Block-Erase Operation

These devices offer both Sector-Erase and Block-Erase operations. These operations allow the system to erase the devices on a sector-by-sector (or block-by-block) basis. The sector architecture is based on a uniform sector size of 2 KWord. The Block-Erase mode is based on a uniform block size of 32 KWord. The Sector-Erase operation is initiated by executing a six-byte command sequence with a Sector-Erase command (50H) and sector address (SA) in the last bus cycle. The Block-Erase operation is initiated by executing a six-byte command sequence with Block-Erase command (30H) and block address (BA) in the last bus cycle. The sector or block address is latched on the falling edge of the sixth WE# pulse, while the command (30H or 50H) is latched on the rising edge of the sixth WE# pulse. The internal Erase operation begins after the sixth WE# pulse. Any commands issued during the Block- or Sector-Erase operation are ignored except Erase-Suspend and Erase-Resume. See Figures 13 and 14 for timing waveforms.

## Flash Chip-Erase Operation

The SST34HF32xx provide a Chip-Erase operation, which allows the user to erase all flash sectors/blocks to the "1" state. This is useful when the device must be quickly erased.

The Chip-Erase operation is initiated by executing a six-byte command sequence with Chip-Erase command (10H) at address 555H in the last byte sequence. The Erase operation begins with the rising edge of the sixth WE# or BEF#, whichever occurs first. During the Erase operation, the only valid read is Toggle Bits or Data# Polling. See Table 6 for the command sequence, Figure 12 for timing diagram, and Figure 26 for the flowchart. Any commands issued during the Chip-Erase operation are ignored. When WP# is low, any attempt to Chip-Erase will be ignored.

## Flash Erase-Suspend/-Resume Operations

The Erase-Suspend operation temporarily suspends a Sector- or Block-Erase operation thus allowing data to be read from any memory location, or program data into any sector/block that is not suspended for an Erase operation. The operation is executed by issuing a one-byte command sequence with Erase-Suspend command (B0H). The device automatically enters read mode no more than 10  $\mu$ s after the Erase-Suspend command had been issued. ( $T_{ES}$  maximum latency equals 10  $\mu$ s.) Valid data can be read from any sector or block that is not suspended from an Erase operation. Reading at address location within erase-suspended sectors/blocks will output DQ<sub>2</sub> toggling and DQ<sub>6</sub> at "1". While in Erase-Suspend mode, a Program operation is allowed except for the sector or block selected for Erase-Suspend. To resume Sector-Erase or Block-Erase operation which has been suspended, the system must issue an Erase-Resume command. The operation is executed by issuing a one-byte command sequence with Erase Resume command (30H) at any address in the one-byte sequence.



### Flash Write Operation Status Detection

The SST34HF32xx provide one hardware and two software means to detect the completion of a Write (Program or Erase) cycle, in order to optimize the system Write cycle time. The hardware detection uses the Ready/Busy# (RY/BY#) pin. The software detection includes two status bits: Data# Polling (DQ<sub>7</sub>) and Toggle Bit (DQ<sub>6</sub>). The End-of-Write detection mode is enabled after the rising edge of WE#, which initiates the internal Program or Erase operation.

The actual completion of the nonvolatile write is asynchronous with the system; therefore, either a Ready/Busy# (RY/BY#), Data# Polling (DQ<sub>7</sub>) or Toggle Bit (DQ<sub>6</sub>) read may be simultaneous with the completion of the Write cycle. If this occurs, the system may possibly get an erroneous result, i.e., valid data may appear to conflict with either DQ<sub>7</sub> or DQ<sub>6</sub>. In order to prevent spurious rejection, if an erroneous result occurs, the software routine should include a loop to read the accessed location an additional two (2) times. If both reads are valid, then the device has completed the Write cycle, otherwise the rejection is valid.

### Ready/Busy# (RY/BY#)

The SST34HF32xx include a Ready/Busy# (RY/BY#) output signal. RY/BY# is an open drain output pin that indicates whether an Erase or Program operation is in progress. Since RY/BY# is an open drain output, it allows several devices to be tied in parallel to V<sub>DD</sub> via an external pull-up resistor. After the rising edge of the final WE# pulse in the command sequence, the RY/BY# status is valid. When RY/BY# is actively pulled low, it indicates that an Erase or Program operation is in progress. When RY/BY# is high (Ready), the devices may be read or left in standby mode.

### Byte/Word (CIOF)

The device includes a CIOF pin to control whether the device data I/O pins operate x8 or x16. If the CIOF pin is at logic "1" (V<sub>IH</sub>) the device is in x16 data configuration: all data I/O pins DQ<sub>0</sub>-DQ<sub>15</sub> are active and controlled by BEF# and OE#.

If the CIOF pin is at logic "0", the device is in x8 data configuration: only data I/O pins DQ<sub>0</sub>-DQ<sub>7</sub> are active and controlled by BEF# and OE#. The remaining data pins DQ<sub>8</sub>-DQ<sub>14</sub> are at Hi-Z, while pin DQ<sub>15</sub> is used as the address input A<sub>-1</sub> for the Least Significant Bit of the address bus.

### Flash Data# Polling (DQ<sub>7</sub>)

When the devices are in an internal Program operation, any attempt to read DQ<sub>7</sub> will produce the complement of the true data. Once the Program operation is completed, DQ<sub>7</sub> will produce true data. During internal Erase operation, any attempt to read DQ<sub>7</sub> will produce a '0'. Once the internal Erase operation is completed, DQ<sub>7</sub> will produce a '1'. The Data# Polling is valid after the rising edge of fourth WE# (or BEF#) pulse for Program operation. For Sector-, Block-, or Chip-Erase, the Data# Polling is valid after the rising edge of sixth WE# (or BEF#) pulse. See Figure 10 for Data# Polling (DQ<sub>7</sub>) timing diagram and Figure 23 for a flowchart.



### Toggle Bits (DQ<sub>6</sub> and DQ<sub>2</sub>)

During the internal Program or Erase operation, any consecutive attempts to read DQ<sub>6</sub> will produce alternating “1”s and “0”s, i.e., toggling between 1 and 0. When the internal Program or Erase operation is completed, the DQ<sub>6</sub> bit will stop toggling. The device is then ready for the next operation. The toggle bit is valid after the rising edge of the fourth WE# (or BEF#) pulse for Program operations. For Sector-, Block-, or Chip-Erase, the toggle bit (DQ<sub>6</sub>) is valid after the rising edge of sixth WE# (or BEF#) pulse. DQ<sub>6</sub> will be set to “1” if a Read operation is attempted on an Erase-suspended Sector/Block. If Program operation is initiated in a sector/block not selected in Erase-Suspend mode, DQ<sub>6</sub> will toggle.

An additional Toggle Bit is available on DQ<sub>2</sub>, which can be used in conjunction with DQ<sub>6</sub> to check whether a particular sector is being actively erased or erase-suspended. Table 1 shows detailed status bit information. The Toggle Bit (DQ<sub>2</sub>) is valid after the rising edge of the last WE# (or BEF#) pulse of a Write operation. See Figure 11 for Toggle Bit timing diagram and Figure 23 for a flowchart.

**TABLE 1: Write Operation Status**

Status		DQ <sub>7</sub>	DQ <sub>6</sub>	DQ <sub>2</sub>	RY/BY#
Normal Operation	Standard Program	DQ7#	Toggle	No Toggle	0
	Standard Erase	0	Toggle	Toggle	0
Erase-Suspend Mode	Read From Erase Suspended Sector/Block	1	1	Toggle	1
	Read From Non-Erase Suspended Sector/Block	Data	Data	Data	1
	Program	DQ7#	Toggle	No Toggle	0

T1.1 1335

**Note:** DQ<sub>7</sub>, DQ<sub>6</sub>, and DQ<sub>2</sub> require a valid address when reading status information. The address must be in the bank where the operation is in progress in order to read the operation status. If the address is pointing to a different bank (not busy), the device will output array data.

### Data Protection

The SST34HF32xx provide both hardware and software features to protect nonvolatile data from inadvertent writes.

#### Hardware Data Protection

**Noise/Glitch Protection:** A WE# or BEF# pulse of less than 5 ns will not initiate a Write cycle.

**V<sub>DD</sub> Power Up/Down Detection:** The Write operation is inhibited when V<sub>DD</sub> is less than 1.5V.

**Write Inhibit Mode:** Forcing OE# low, BEF# high, or WE# high will inhibit the Write operation. This prevents inadvertent writes during power-up or power-down.

#### Hardware Block Protection

The SST34HF32xx provide a hardware block protection which protects the outermost 8 KWord/16 KByte in Bank 1. The block is protected when WP# is held low. When WP# is held low and a Block-Erase command is issued to the protected block, the data in the outermost 8 KWord/16 KByte section will be protected. The rest of the block will be erased. See Table 3 for Block-Protection location.

A user can disable block protection by driving WP# high thus allowing erase or program of data into the protected sectors. WP# must be held high prior to issuing the write command and remain stable until after the entire Write operation has completed. If WP# is left floating, it is internally held high via a pull-up resistor, and the Boot Block is unprotected, enabling Program and Erase operations on that block.

#### Hardware Reset (RST#)

The RST# pin provides a hardware method of resetting the device to read array data. When the RST# pin is held low for at least T<sub>RP</sub>, any in-progress operation will terminate and return to Read mode (see Figure 19). When no internal Program/Erase operation is in progress, a minimum period of T<sub>RHR</sub> is required after RST# is driven high before a valid Read can take place (see Figure 18).

The Erase operation that has been interrupted needs to be reinitiated after the device resumes normal operation mode to ensure data integrity. See Figures 18 and 19 for timing diagrams.



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## Software Data Protection (SDP)

The SST34HF32xx provide the JEDEC standard Software Data Protection scheme for all data alteration operations, i.e., Program and Erase. Any Program operation requires the inclusion of the three-byte sequence. The three-byte load sequence is used to initiate the Program operation, providing optimal protection from inadvertent Write operations, e.g., during the system power-up or power-down. Any Erase operation requires the inclusion of six-byte sequence. The SST34HF32xx are shipped with the Software Data Protection permanently enabled. See Table 6 for the specific software command codes. During SDP command sequence, invalid commands will abort the device to Read mode within  $T_{RC}$ . The contents of  $DQ_{15}$ - $DQ_8$  are "Don't Care" during any SDP command sequence.

## Common Flash Memory Interface (CFI)

These devices also contain the CFI information to describe the characteristics of the devices. In order to enter the CFI Query mode, the system must write the three-byte sequence, same as the Software ID Entry command with 98H (CFI Query command) to address  $BK_X555H$  in the last byte sequence. In order to enter the CFI Query mode, the system can also use the one-byte sequence with  $BK_X555H$  on Address and 98H on Data Bus. See Figure 16 for CFI Entry and Read timing diagram. Once the device enters the CFI Query mode, the system can read CFI data at the addresses given in Tables 7 through 9. The system must write the CFI Exit command to return to Read mode from the CFI Query mode.

## Security ID

The SST34HF32xx devices offer a 136-word Security ID space. The Secure ID space is divided into two segments—one 128-bit factory programmed segment and one 128-word (256-byte) user-programmed segment. The first segment is programmed and locked at SST with a unique, 128-bit number. The user segment is left un-programmed for the customer to program as desired.

To program the user segment of the Security ID, the user must use the Security ID Program command. End-of-Write status is checked by reading the toggle bits. Data# Polling is not used for Security ID End-of-Write detection. Once programming is complete, the Sec ID should be locked using the User-Sec-ID-Program-Lock-Out. This disables any future corruption of this space. Note that regardless of whether or not the Sec ID is locked, neither Sec ID segment can be erased. The Secure ID space can be queried by executing a three-byte command sequence with Query-Sec-ID command (88H) at address 555H in the last byte sequence. To exit this mode, the Exit-Sec-ID command should be executed. Refer to Table 6 for more details.



### Product Identification

The Product Identification mode identifies the device as either SST34HF3282 or SST34HF32x4 and manufacturer as SST. This mode may be accessed by software operations only. The hardware device ID Read operation, which is typically used by programmers cannot be used on this device because of the shared lines between flash and PSRAM in the multi-chip package. Therefore, application of high voltage to pin A<sub>9</sub> may damage this device. Users may use the software Product Identification operation to identify the part (i.e., using the device ID) when using multiple manufacturers in the same socket. For details, see Tables 5 and 6 for software operation, Figure 15 for the Software ID Entry and Read timing diagram and Figure 24 for the ID Entry command sequence flowchart.

**TABLE 2: Product Identification**

	ADDRESS	DATA
Manufacturer's ID	BK0000H	00BFH
Device ID		
SST34HF3282	BK0001H	7351H
SST34HF3244/3284	BK0001H	7353H

T2.0 1335

**Note:** BK = Bank Address (A<sub>20</sub>-A<sub>18</sub>)

### Product Identification Mode Exit/ CFI Mode Exit

In order to return to the standard Read mode, the Software Product Identification mode must be exited. Exit is accomplished by issuing the Software ID Exit command sequence, which returns the device to the Read mode. This command may also be used to reset the device to the Read mode after any inadvertent transient condition that apparently causes the device to behave abnormally, e.g., not read correctly. Please note that the Software ID Exit command is ignored during an internal Program or Erase operation. See Table 6 for software command codes, Figure 17 for timing waveform and Figure 24 for a flowchart.

### PSRAM Operation

With BES1# low, BES2 and BEF# high, the SST34HF32xx operate as either 256K x16 or 512K x16 CMOS PSRAM, with fully static operation requiring no external clocks or timing strobes. The SST34HF32xx PSRAM is mapped into the first 512 KWord address space. When BES1#, BEF# are high and BES2 is low, all memory banks are deselected and the device enters standby. Read and Write cycle times are equal. The control signals UBS# and LBS# pro-

vide access to the upper data byte and lower data byte. See Table 5 for x16 PSRAM Read and Write data byte control modes of operation.

### PSRAM Read

The PSRAM Read operation of the SST34HF32xx is controlled by OE# and BES1#, both have to be low with WE# and BES2 high for the system to obtain data from the outputs. BES1# and BES2 are used for PSRAM bank selection. OE# is the output control and is used to gate data from the output pins. The data bus is in high impedance state when OE# is high. Refer to the Read cycle timing diagram, Figure 4, for further details.

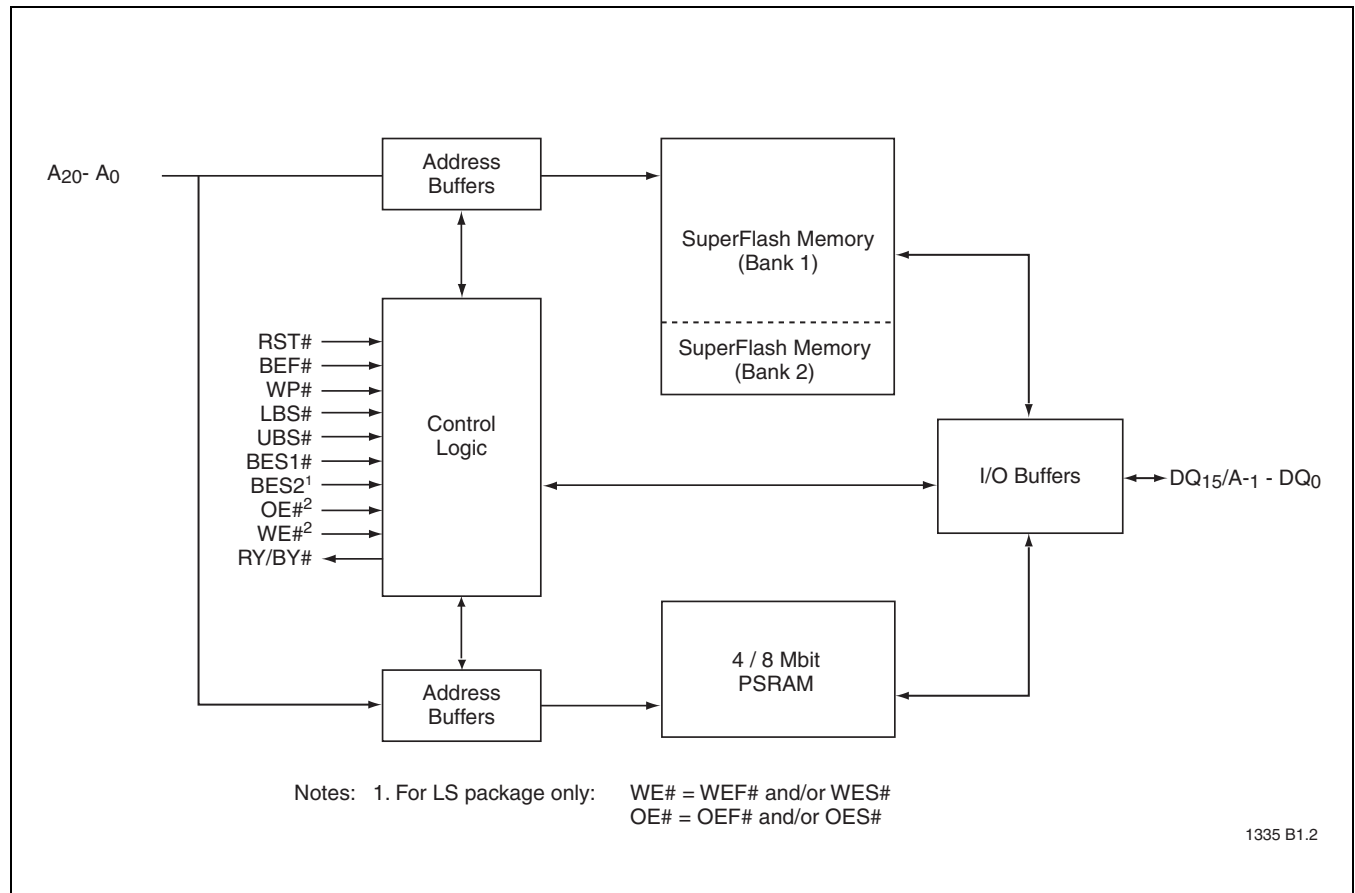
### PSRAM Write

The PSRAM Write operation of the SST34HF32xx is controlled by WE# and BES1#, both have to be low, BES2 must be high for the system to write to the PSRAM. During the Word-Write operation, the addresses and data are referenced to the rising edge of either BES1#, WE#, or the falling edge of BES2 whichever occurs first. The write time is measured from the last falling edge of BES#1 or WE# or the rising edge of BES2 to the first rising edge of BES1#, or WE# or the falling edge of BES2. Refer to the Write cycle timing diagrams, Figures 5 and 6, for further details.



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**FIGURE 1: Functional Block Diagram**





TABLE 3: Dual-Bank Memory Organization (1 of 2)

SST34HF3282	SST34HF3244/3284	Block	Block Size	Address Range x8	Address Range x16
Bank 1	Bank 1	BA63	8 KW / 16 KB	3FC000H–3FFFFFFH	1FE000H–1FFFFFFH
			24 KW / 48 KB	3F0000H–3FBFFFFH	1F8000H–1FDFFFFH
		BA62	32 KW / 64 KB	3E0000H–3EFFFFFFH	1F0000H–1F7FFFFH
		BA61	32 KW / 64 KB	3D0000H–3DFFFFFFH	1E8000H–1EFFFFFFH
		BA60	32 KW / 64 KB	3C0000H–3CFFFFFFH	1E0000H–1E7FFFFH
		BA59	32 KW / 64 KB	3B0000H–3BFFFFFFH	1D8000H–1DFFFFFFH
		BA58	32 KW / 64 KB	3A0000H–3AFFFFFFH	1D0000H–1D7FFFFH
		BA57	32 KW / 64 KB	390000H–39FFFFFFH	1C8000H–1CFFFFFFH
		BA56	32 KW / 64 KB	380000H–38FFFFFFH	1C0000H–1C7FFFFH
Bank 2	Bank 1	BA55	32 KW / 64 KB	370000H–37FFFFFFH	1B8000H–1BFFFFFFH
		BA54	32 KW / 64 KB	360000H–36FFFFFFH	1B0000H–1B7FFFFH
		BA53	32 KW / 64 KB	350000H–35FFFFFFH	1A8000H–1AFFFFFFH
		BA52	32 KW / 64 KB	340000H–34FFFFFFH	1A0000H–1A7FFFFH
		BA51	32 KW / 64 KB	330000H–33FFFFFFH	198000H–19FFFFFFH
		BA50	32 KW / 64 KB	320000H–32FFFFFFH	190000H–197FFFFH
		BA49	32 KW / 64 KB	310000H–31FFFFFFH	188000H–18FFFFFFH
		BA48	32 KW / 64 KB	300000H–30FFFFFFH	180000H–187FFFFH
		BA47	32 KW / 64 KB	2F0000H–2FFFFFFFH	178000H–17FFFFFFH
	Bank 2	BA46	32 KW / 64 KB	2E0000H–2EFFFFFFH	170000H–177FFFFH
		BA45	32 KW / 64 KB	2D0000H–2DFFFFFFH	168000H–16FFFFFFH
		BA44	32 KW / 64 KB	2C0000H–2CFFFFFFH	160000H–167FFFFH
		BA43	32 KW / 64 KB	2B0000H–2BFFFFFFH	158000H–15FFFFFFH
		BA42	32 KW / 64 KB	2A0000H–2AFFFFFFH	150000H–157FFFFH
		BA41	32 KW / 64 KB	290000H–29FFFFFFH	148000H–14FFFFFFH
		BA40	32 KW / 64 KB	280000H–28FFFFFFH	140000H–147FFFFH
		BA39	32 KW / 64 KB	270000H–27FFFFFFH	138000H–13FFFFFFH
		BA38	32 KW / 64 KB	260000H–26FFFFFFH	130000H–137FFFFH
		BA37	32 KW / 64 KB	250000H–25FFFFFFH	128000H–12FFFFFFH
		BA36	32 KW / 64 KB	240000H–24FFFFFFH	120000H–127FFFFH
		BA35	32 KW / 64 KB	230000H–23FFFFFFH	118000H–11FFFFFFH
		BA34	32 KW / 64 KB	220000H–22FFFFFFH	110000H–117FFFFH
		BA33	32 KW / 64 KB	210000H–21FFFFFFH	108000H–10FFFFFFH
		BA32	32 KW / 64 KB	200000H–20FFFFFFH	100000H–107FFFFH
		BA31	32 KW / 64 KB	1F0000H–1FFFFFFH	0F8000H–0FFFFFFH
		BA30	32 KW / 64 KB	1E0000H–1EFFFFFFH	0F0000H–0F7FFFFH
		BA29	32 KW / 64 KB	1D0000H–1DFFFFFFH	0E8000H–0EFFFFFFH
		BA28	32 KW / 64 KB	1C0000H–1CFFFFFFH	0E0000H–0E7FFFFH
		BA27	32 KW / 64 KB	1B0000H–1BFFFFFFH	0D8000H–0DFFFFFFH
		BA26	32 KW / 64 KB	1A0000H–1AFFFFFFH	0D0000H–0D7FFFFH
		BA25	32 KW / 64 KB	190000H–19FFFFFFH	0C8000H–0CFFFFFFH
		BA24	32 KW / 64 KB	180000H–18FFFFFFH	0C0000H–0C7FFFFH
		BA23	32 KW / 64 KB	170000H–17FFFFFFH	0B8000H–0BFFFFFFH
		BA22	32 KW / 64 KB	160000H–16FFFFFFH	0B0000H–0B7FFFFH



# 32 Mbit Concurrent SuperFlash + 4/8 Mbit PSRAM ComboMemory SST34HF3244 / SST34HF3282 / SST34HF3284

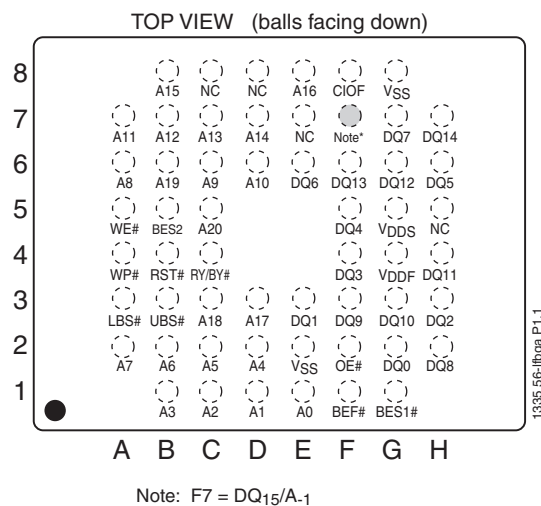
Data Sheet

**TABLE 3: Dual-Bank Memory Organization (Continued) (2 of 2)**

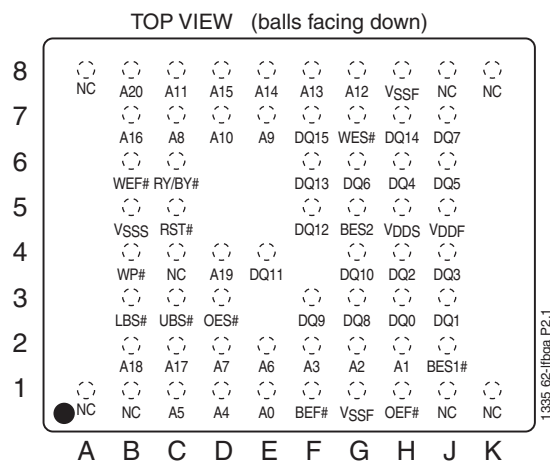
SST34HF3282	SST34HF3244/3284	Block	Block Size	Address Range x8	Address Range x16
<b>Bank 2</b>	<b>Bank 2</b>	BA21	32 KW / 64 KB	150000H—15FFFFH	0A8000H—0AFFFFH
		BA20	32 KW / 64 KB	140000H—14FFFFH	0A0000H—0A7FFFH
		BA19	32 KW / 64 KB	130000H—13FFFFH	098000H—09FFFFH
		BA18	32 KW / 64 KB	120000H—12FFFFH	090000H—097FFFH
		BA17	32 KW / 64 KB	110000H—11FFFFH	088000H—08FFFFH
		BA16	32 KW / 64 KB	100000H—10FFFFH	080000H—087FFFH
		BA15	32 KW / 64 KB	0F0000H—0FFFFFH	078000H—07FFFFH
		BA14	32 KW / 64 KB	0E0000H—0EFFFFH	070000H—077FFFH
		BA13	32 KW / 64 KB	0D0000H—0DFFFFH	068000H—06FFFFH
		BA12	32 KW / 64 KB	0C0000H—0CFFFFH	060000H—067FFFH
		BA11	32 KW / 64 KB	0B0000H—0BFFFFH	058000H—05FFFFH
		BA10	32 KW / 64 KB	0A0000H—0AFFFFH	050000H—057FFFH
		BA9	32 KW / 64 KB	090000H—09FFFFH	048000H—04FFFFH
		BA8	32 KW / 64 KB	080000H—08FFFFH	040000H—047FFFH
		BA7	32 KW / 64 KB	070000H—07FFFFH	038000H—03FFFFH
		BA6	32 KW / 64 KB	060000H—06FFFFH	030000H—037FFFH
		BA5	32 KW / 64 KB	050000H—05FFFFH	028000H—02FFFFH
		BA4	32 KW / 64 KB	040000H—04FFFFH	020000H—027FFFH
		BA3	32 KW / 64 KB	030000H—03FFFFH	018000H—01FFFFH
		BA2	32 KW / 64 KB	020000H—02FFFFH	010000H—017FFFH
		BA1	32 KW / 64 KB	010000H—01FFFFH	008000H—00FFFFH
		BA0	32 KW / 64 KB	000000H—00FFFFH	000000H—007FFFH

T3.0 1335

## PIN DESCRIPTION



**FIGURE 2: Pin Assignments for 56-ball LFBGA (8mm x 10mm)**



**FIGURE 3: Pin Assignments for 62-ball LFBGA (8mm x 10mm)**



# 32 Mbit Concurrent SuperFlash + 4/8 Mbit PSRAM ComboMemory

## SST34HF3244 / SST34HF3282 / SST34HF3284

### Data Sheet

**TABLE 4: Pin Description**

Symbol	Pin Name	Functions
A <sub>MS</sub> <sup>1</sup> to A <sub>0</sub>	Address Inputs	To provide flash address, A <sub>20</sub> -A <sub>0</sub> . To provide PSRAM address, A <sub>MS</sub> -A <sub>0</sub>
DQ <sub>14</sub> -DQ <sub>0</sub>	Data Inputs/Outputs	To output data during Read cycles and receive input data during Write cycles. Data is internally latched during a flash Erase/Program cycle. The outputs are in tri-state when OE# is high or BES1# is high or BES2 is low and BEF# is high.
DQ <sub>15</sub> /A <sub>-1</sub>	Data Input/Output and LBS Address	DQ <sub>15</sub> is used as data I/O pin when in x16 mode (CIOF = "1") A <sub>-1</sub> is used as the LBS address pin when in x8 mode (CIOF = "0")
BEF#	Flash Memory Bank Enable	To activate the Flash memory bank when BEF# is low
BES1#	PSRAM Memory Bank Enable	To activate the PSRAM memory bank when BES1# is low
BES2	PSRAM Memory Bank Enable	To activate the PSRAM memory bank when BES2 is high
OEF# <sup>2</sup>	Output Enable	To gate the data output buffers for Flash <sup>2</sup> only
OES# <sup>2</sup>	Output Enable	To gate the data output buffers for SRAM <sup>2</sup> only
WEF# <sup>2</sup>	Write Enable	To control the Write operations for Flash <sup>2</sup> only
WES# <sup>2</sup>	Write Enable	To control the Write operations for SRAM <sup>2</sup> only
OE#	Output Enable	To gate the data output buffers
WE#	Write Enable	To control the Write operations
CIOF	Byte Selection for Flash	When low, select Byte mode. When high, select Word mode.
UBS#	Upper Byte Control (PSRAM)	To enable DQ <sub>15</sub> -DQ <sub>8</sub>
LBS#	Lower Byte Control (PSRAM)	To enable DQ <sub>7</sub> -DQ <sub>0</sub>
WP#	Write Protect	To protect and unprotect the bottom 8 KWord (4 sectors) from Erase or Program operation
RST#	Reset	To Reset and return the device to Read mode
RY/BY#	Ready/Busy#	To output the status of a Program or Erase Operation RY/BY# is a open drain output, so a 10KΩ - 100KΩ pull-up resistor is required to allow RY/BY# to transition high indicating the device is ready to read.
V <sub>SSF</sub> <sup>2</sup>	Ground	Flash <sup>2</sup> only
V <sub>SSS</sub> <sup>2</sup>	Ground	SRAM <sup>2</sup> only
V <sub>SS</sub>	Ground	
V <sub>DDF</sub>	Power Supply (Flash)	2.7-3.3V Power Supply to Flash only
V <sub>DDS</sub>	Power Supply (PSRAM)	2.7-3.3V Power Supply to PSRAM only
NC	No Connection	Unconnected pins

T4.0 1335

1. A<sub>MS</sub> = Most Significant Address  
A<sub>MS</sub> = A<sub>17</sub> for SST34HF3244 and A<sub>18</sub> for SST34HF328x
2. LSE package only



TABLE 5: Operational Modes Selection for x16 PSRAM

Mode	BEF# <sup>1</sup>	BES1# <sup>1,2</sup>	BES2# <sup>1,2</sup>	OE# <sup>2,3</sup>	WE# <sup>2,3</sup>	LBS# <sup>2</sup>	UBS# <sup>2</sup>	DQ <sub>15-8</sub>		
								DQ <sub>7-0</sub>	CIOF = V <sub>IH</sub>	CIOF = V <sub>IL</sub>
Full Standby	V <sub>IH</sub>	V <sub>IH</sub>	X	X	X	X	X	HIGH-Z	HIGH-Z	HIGH-Z
		X	V <sub>IL</sub>	X	X	X	X			
Output Disable	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IH</sub>	V <sub>IH</sub>	X	X	HIGH-Z	HIGH-Z	HIGH-Z
		V <sub>IL</sub>	V <sub>IH</sub>	X	X	V <sub>IH</sub>	V <sub>IH</sub>			
	V <sub>IL</sub>	V <sub>IH</sub>	X	V <sub>IH</sub>	V <sub>IH</sub>	X	X	HIGH-Z	HIGH-Z	HIGH-Z
		X	V <sub>IL</sub>							
Flash Read	V <sub>IL</sub>	V <sub>IH</sub>	X	V <sub>IL</sub>	V <sub>IH</sub>	X	X	D <sub>OUT</sub>	D <sub>OUT</sub>	DQ <sub>14-8</sub> = HIGH-Z DQ <sub>15</sub> = A <sub>-1</sub>
		X	V <sub>IL</sub>							
Flash Write	V <sub>IL</sub>	V <sub>IH</sub>	X	V <sub>IH</sub>	V <sub>IL</sub>	X	X	D <sub>IN</sub>	D <sub>IN</sub>	DQ <sub>14-8</sub> = HIGH-Z DQ <sub>15</sub> = A <sub>-1</sub>
		X	V <sub>IL</sub>							
Flash Erase	V <sub>IL</sub>	V <sub>IH</sub>	X	V <sub>IH</sub>	V <sub>IL</sub>	X	X	X	X	X
		X	V <sub>IL</sub>							
PSRAM Read	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IL</sub>	D <sub>OUT</sub>	D <sub>OUT</sub>	D <sub>OUT</sub>
						V <sub>IH</sub>	V <sub>IL</sub>	HIGH-Z	D <sub>OUT</sub>	D <sub>OUT</sub>
						V <sub>IL</sub>	V <sub>IH</sub>	D <sub>OUT</sub>	HIGH-Z	HIGH-Z
PSRAM Write	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IH</sub>	X	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IL</sub>	D <sub>IN</sub>	D <sub>IN</sub>	D <sub>IN</sub>
						V <sub>IH</sub>	V <sub>IL</sub>	HIGH-Z	D <sub>IN</sub>	D <sub>IN</sub>
						V <sub>IL</sub>	V <sub>IH</sub>	D <sub>IN</sub>	HIGH-Z	HIGH-Z
Product Identification <sup>4</sup>	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>	X	X	Manufacturer's ID <sup>5</sup> Device ID <sup>5</sup>		

T5.1 1335

1. Do not apply BEF# = V<sub>IL</sub>, BES1# = V<sub>IL</sub> and BES2 = V<sub>IH</sub> at the same time
2. X can be V<sub>IL</sub> or V<sub>IH</sub>, but no other value.
3. OE# = OEF# and OES#  
WE# = WEF# and WES# for LSE package only
4. Software mode only
5. With A<sub>19</sub>-A<sub>18</sub> = V<sub>IL</sub>, SST Manufacturer's ID = BFH, is read with A<sub>0</sub>=0,  
SST34HF3282 Device ID = 7351H, is read with A<sub>0</sub>=1  
SST34HF32x4 Device ID = 7353H, is read with A<sub>0</sub>=1



# 32 Mbit Concurrent SuperFlash + 4/8 Mbit PSRAM ComboMemory SST34HF3244 / SST34HF3282 / SST34HF3284

## Data Sheet

**TABLE 6: Software Command Sequence**

Command Sequence	1st Bus Write Cycle		2nd Bus Write Cycle		3rd Bus Write Cycle		4th Bus Write Cycle		5th Bus Write Cycle		6th Bus Write Cycle	
	Addr <sup>1</sup>	Data <sup>2</sup>	Addr <sup>1</sup>	Data <sup>2</sup>	Addr <sup>1</sup>	Data <sup>2</sup>	Addr <sup>1</sup>	Data <sup>2</sup>	Addr <sup>1</sup>	Data <sup>2</sup>	Addr <sup>1</sup>	Data <sup>2</sup>
Word-Program	555H	AAH	2AAH	55H	555H	A0H	WA <sup>3</sup>	Data				
Sector-Erase	555H	AAH	2AAH	55H	555H	80H	555H	AAH	2AAH	55H	SA <sub>X</sub> <sup>4</sup>	50H
Block-Erase	555H	AAH	2AAH	55H	555H	80H	555H	AAH	2AAH	55H	BA <sub>X</sub> <sup>4</sup>	30H
Chip-Erase	555H	AAH	2AAH	55H	555H	80H	555H	AAH	2AAH	55H	555H	10H
Erase-Suspend	XXXXH	B0H										
Erase-Resume	XXXXH	30H										
Query Sec ID <sup>5</sup>	555H	AAH	2AAH	55H	555H	88H						
User-Security-ID-Program	555H	AAH	2AAH	55H	555H	A5H	SIWA <sup>6</sup>	Data				
User-Security-ID-Program-Lock-out <sup>7</sup>	555H	AAH	2AAH	55H	555H	85H	XXH	0000H				
Software ID Entry <sup>8</sup>	555H	AAH	2AAH	55H	BK <sub>X</sub> <sup>9</sup> 555H	90H						
CFI Query Entry	555H	AAH	2AAH	55H	BK <sub>X</sub> <sup>4</sup> 555H	98H						
CFI Query Entry	BK <sub>X</sub> <sup>4</sup> 55H	98H										
Software ID Exit/ CFI Exit/ Sec ID Exit <sup>10,11</sup>	555H	AAH	2AAH	55H	555H	F0H						
Software ID Exit/ CFI Exit/ Sec ID Exit <sup>10,11</sup>	XXH	F0H										

T6.1 1335

1. Address format A<sub>10</sub>-A<sub>0</sub> (Hex), Addresses A<sub>20</sub>-A<sub>11</sub> can be V<sub>IL</sub> or V<sub>IH</sub>, but no other value, for the command sequence when in x16 mode.  
When in x8 mode, Addresses A<sub>20</sub>-A<sub>12</sub>, Address A<sub>1</sub> and DQ<sub>14</sub>-DQ<sub>8</sub> can be V<sub>IL</sub> or V<sub>IH</sub>, but no other value, for the command sequence.
2. DQ<sub>15</sub>-DQ<sub>8</sub> can be V<sub>IL</sub> or V<sub>IH</sub>, but no other value, for the command sequence
3. WA = Program Word/Byte address
4. SA<sub>X</sub> for Sector-Erase; uses A<sub>20</sub>-A<sub>11</sub> address lines  
BA<sub>X</sub> for Block-Erase; uses A<sub>20</sub>-A<sub>15</sub> address lines
5. For SST34HF32xx the Security ID Address Range is:  
(x16 mode) = 000000H to 000087H, (x8 mode) = 000000H to 00010FH  
SST ID is read at Address Range (x16 mode) = 000000H to 000007H (x8 mode) = 000000H to 00000FH  
User ID is read at Address Range (x16 mode) = 000008H to 000087H (x8 mode) = 000010H to 00010FH  
Lock Status is read at Address 0000FFH (x16) or 0001FFH (x8). Unlocked: DQ3 = 1 / Locked: DQ3 = 0.
6. SIWA = User Security ID Program Word/Byte address  
For SST34HF32xx, valid Address Range is  
(x16 mode) = 000008H-000087H (x8 mode) = 000010H-00010FH.  
All 4 cycles of User Security ID Program and Program Lock-out must be completed before going back to Read-Array mode.
7. The User-Security-ID-Program-Lock-out command must be executed in x16 mode. (CIOF = V<sub>IH</sub>)
8. The device does not remain in Software Product Identification mode if powered down.
9. A<sub>19</sub> and A<sub>18</sub> = V<sub>IL</sub>
10. Both Software ID Exit operations are equivalent
11. If users never lock after programming, User Sec ID can be programmed over the previously unprogrammed bits (data=1) using the User Sec ID mode again (the programmed "0" bits cannot be reversed to "1").



**TABLE 7: CFI Query Identification String<sup>1</sup>**

Address x16 Mode	Address x8 Mode	Data <sup>2</sup>	Description
10H 11H 12H	20H 22H 24H	0051H 0052H 0059H	Query Unique ASCII string "QRY"
13H 14H	26H 28H	0002H 0000H	Primary OEM command set
15H 16H	2AH 2CH	0000H 0000H	Address for Primary Extended Table
17H 18H	2EH 30H	0000H 0000H	Alternate OEM command set (00H = none exists)
19H 1AH	32H 34H	0000H 0000H	Address for Alternate OEM extended Table (00H = none exists)

T7.1 1335

1. Refer to CFI publication 100 for more details.
2. In x8 mode, only the lower byte of data is output.

**TABLE 8: System Interface Information**

Address x16 Mode	Address x8 Mode	Data <sup>1</sup>	Description
1BH	36H	0027H	V <sub>DD</sub> Min (Program/Erase) DQ <sub>7</sub> -DQ <sub>4</sub> : Volts, DQ <sub>3</sub> -DQ <sub>0</sub> : 100 millivolts
1CH	38H	0036H	V <sub>DD</sub> Max (Program/Erase) DQ <sub>7</sub> -DQ <sub>4</sub> : Volts, DQ <sub>3</sub> -DQ <sub>0</sub> : 100 millivolts
1DH	3AH	0000H	V <sub>PP</sub> min (00H = no V <sub>PP</sub> pin)
1EH	3CH	0000H	V <sub>PP</sub> max (00H = no V <sub>PP</sub> pin)
1FH	3EH	0004H	Typical time out for Program 2 <sup>N</sup> μs (2 <sup>4</sup> = 16 μs)
20H	40H	0000H	Typical time out for min size buffer program 2 <sup>N</sup> μs (00H = not supported)
21H	42H	0004H	Typical time out for individual Sector/Block-Erase 2 <sup>N</sup> ms (2 <sup>4</sup> = 16 ms)
22H	44H	0006H	Typical time out for Chip-Erase 2 <sup>N</sup> ms (2 <sup>6</sup> = 64 ms)
23H	46H	0001H	Maximum time out for Program 2 <sup>N</sup> times typical (2 <sup>1</sup> x 2 <sup>4</sup> = 32 μs)
24H	48H	0000H	Maximum time out for buffer program 2 <sup>N</sup> times typical
25H	4AH	0001H	Maximum time out for individual Sector-/Block-Erase 2 <sup>N</sup> times typical (2 <sup>1</sup> x 2 <sup>4</sup> = 32 ms)
26H	4CH	0001H	Maximum time out for Chip-Erase 2 <sup>N</sup> times typical (2 <sup>1</sup> x 2 <sup>6</sup> = 128 ms)

T8.0 1335

1. In x8 mode, only the lower byte of data is output.



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**TABLE 9: Device Geometry Information**

Address x16 Mode	Address x8 Mode	Data <sup>1</sup>	Description
27H	4EH	0016H	Device size = $2^N$ Bytes (16H = 22; $2^{22}$ = 4 MByte)
28H	50H	0002H	Flash Device Interface description; 0002H = x8/x16 asynchronous interface
29H	52H	0000H	
2AH	54H	0000H	Maximum number of bytes in multi-byte write = $2^N$ (00H = not supported)
2BH	56H	0000H	
2CH	58H	0002H	Number of Erase Sector/Block sizes supported by device
2DH	5AH	003FH	Block Information (y + 1 = Number of blocks; z x 256B = block size)
2EH	5CH	0000H	y = 63 + 1 = 64 blocks (003FH = 63)
2FH	5EH	0000H	
30H	60H	0001H	z = 256 x 256 Bytes = 64 KByte/block (0100H = 256)
31H	62H	00FFH	Sector Information (y + 1 = Number of sectors; z x 256B = sector size)
32H	64H	0003H	y = 1023 + 1 = 1024 sectors (03FFH = 1023)
33H	66H	0010H	
34H	68H	0000H	z = 16 x 256 Bytes = 4 KByte/sector (0010H = 16)

T9.2 1335

1. In x8 mode, only the lower byte of data is output.



**32 Mbit Concurrent SuperFlash + 4/8 Mbit PSRAM ComboMemory**  
**SST34HF3244 / SST34HF3282 / SST34HF3284**



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**Absolute Maximum Stress Ratings** (Applied conditions greater than those listed under “Absolute Maximum Stress Ratings” may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these conditions or conditions greater than those defined in the operational sections of this data sheet is not implied. Exposure to absolute maximum stress rating conditions may affect device reliability.)

Operating Temperature ..... -20°C to +85°C  
Storage Temperature ..... -65°C to +125°C  
D. C. Voltage on Any Pin to Ground Potential ..... -0.5V to  $V_{DD}^1+0.3V$   
Transient Voltage (<20 ns) on Any Pin to Ground Potential ..... -1.0V to  $V_{DD}^1+1.0V$   
Package Power Dissipation Capability ( $T_A = 25^\circ C$ ) ..... 1.0W  
Surface Mount Solder Reflow Temperature<sup>2</sup> ..... 260°C for 10 seconds  
Output Short Circuit Current<sup>3</sup> ..... 50 mA

1.  $V_{DD} = V_{DDF}$  and  $V_{DDS}$
2. Excluding certain with-Pb 32-PLCC units, all packages are 260°C capable in both non-Pb and with-Pb solder versions.  
Certain with-Pb 32-PLCC package types are capable of 240°C for 10 seconds; please consult the factory for the latest information.
3. Outputs shorted for no more than one second. No more than one output shorted at a time.

**OPERATING RANGE**

Range	Ambient Temp	$V_{DD}$
Commercial	0°C to +70°C	2.7-3.3V
Extended	-20°C to +85°C	2.7-3.3V

**AC CONDITIONS OF TEST**

Input Rise/Fall Time	5 ns
Output Load	$C_L = 30$ pF
See Figures 20 and 21	



# 32 Mbit Concurrent SuperFlash + 4/8 Mbit PSRAM ComboMemory SST34HF3244 / SST34HF3282 / SST34HF3284

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**TABLE 10: DC Operating Characteristics ( $V_{DD} = V_{DDF}$  and  $V_{DDS} = 2.7\text{-}3.3\text{V}$ )**

Symbol	Parameter	Limits			Test Conditions
		Min	Max	Units	
$I_{DD}^1$	Active $V_{DD}$ Current				Address input = $V_{ILT}/V_{IHT}$ , at $f=5$ MHz, $V_{DD}=V_{DD}$ Max, all DQs open
	Read				$OE\#=V_{IL}$ , $WE\#=V_{IH}$
	Flash		35	mA	$BEF\#=V_{IL}$ , $BES1\#=V_{IH}$ , or $BES2=V_{IL}$
	PSRAM		30	mA	$BEF\#=V_{IH}$ , $BES1\#=V_{IL}$ , $BES2=V_{IH}$
	Concurrent Operation		60	mA	$BEF\#=V_{IH}$ , $BES1\#=V_{IL}$ , $BES2=V_{IH}$
	Write <sup>2</sup>				$WE\#=V_{IL}$
	Flash		40	mA	$BEF\#=V_{IL}$ , $BES1\#=V_{IH}$ , or $BES2=V_{IL}$ , $OE\#=V_{IH}$
	PSRAM		30	mA	$BEF\#=V_{IH}$ , $BES1\#=V_{IL}$ , $BES2=V_{IH}$
$I_{SB}$	Standby $V_{DD}$ Current		115	$\mu A$	$V_{DD} = V_{DD}$ Max, $BEF\#=BES1\#=V_{IHC}$ , $BES2=V_{ILC}$
$I_{RT}$	Reset $V_{DD}$ Current		30	$\mu A$	$RST\#=GND$
$I_{LI}$	Input Leakage Current		1	$\mu A$	$V_{IN}=GND$ to $V_{DD}$ , $V_{DD}=V_{DD}$ Max
$I_{LIW}$	Input Leakage Current on $WP\#$ pin and $RST\#$ pin		10	$\mu A$	$WP\#=GND$ to $V_{DD}$ , $V_{DD}=V_{DD}$ Max $RST\#=GND$ to $V_{DD}$ , $V_{DD}=V_{DD}$ Max
$I_{LO}$	Output Leakage Current		10	$\mu A$	$V_{OUT}=GND$ to $V_{DD}$ , $V_{DD}=V_{DD}$ Max
$V_{IL}$	Input Low Voltage		0.8	V	$V_{DD}=V_{DD}$ Min
$V_{ILC}$	Input Low Voltage (CMOS)		0.3	V	$V_{DD}=V_{DD}$ Max
$V_{IH}$	Input High Voltage	$0.7 V_{DD}$		V	$V_{DD}=V_{DD}$ Max
$V_{IHC}$	Input High Voltage (CMOS)	$V_{DD}-0.3$		V	$V_{DD}=V_{DD}$ Max
$V_{OLF}$	Flash Output Low Voltage		0.2	V	$I_{OL}=100 \mu A$ , $V_{DD}=V_{DD}$ Min
$V_{OHF}$	Flash Output High Voltage	$V_{DD}-0.2$		V	$I_{OH}=-100 \mu A$ , $V_{DD}=V_{DD}$ Min
$V_{OLS}$	PSRAM Output Low Voltage		0.4	V	$I_{OL}=1 \text{ mA}$ , $V_{DD}=V_{DD}$ Min
$V_{OHS}$	PSRAM Output High Voltage	2.2		V	$I_{OH}=-500 \mu A$ , $V_{DD}=V_{DD}$ Min

T10.0 1335

1. Address input =  $V_{ILT}/V_{IHT}$ ,  $V_{DD}=V_{DD}$  Max (See Figure 20)
2.  $I_{DD}$  active while Erase or Program is in progress.



**TABLE 11: Recommended System Power-up Timings**

Symbol	Parameter	Minimum	Units
$T_{PU-READ}^1$	Power-up to Read Operation	100	$\mu s$
$T_{PU-WRITE}^1$	Power-up to Write Operation	100	$\mu s$

T11.0 1335

1. This parameter is measured only for initial qualification and after a design or process change that could affect this parameter.

**TABLE 12: Capacitance ( $T_A = 25^\circ C$ ,  $f=1$  Mhz, other pins open)**

Parameter	Description	Test Condition	Maximum
$C_{I/O}^1$	I/O Pin Capacitance	$V_{I/O} = 0V$	20 pF
$C_{IN}^1$	Input Capacitance	$V_{IN} = 0V$	16 pF

T12.0 1335

1. This parameter is measured only for initial qualification and after a design or process change that could affect this parameter.

**TABLE 13: Flash Reliability Characteristics**

Symbol	Parameter	Minimum Specification	Units	Test Method
$N_{END}^1$	Endurance	10,000	Cycles	JEDEC Standard A117
$T_{DR}^1$	Data Retention	100	Years	JEDEC Standard A103
$I_{LTH}^1$	Latch Up	$100 + I_{DD}$	mA	JEDEC Standard 78

T13.0 1335

1. This parameter is measured only for initial qualification and after a design or process change that could affect this parameter.



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## AC CHARACTERISTICS

**TABLE 14: PSRAM Read Cycle Timing Parameters**

		Min	Max	Units
T <sub>RCS</sub>	Read Cycle Time	70		ns
T <sub>AAS</sub>	Address Access Time		70	ns
T <sub>BES</sub>	Bank Enable Access Time		70	ns
T <sub>OES</sub>	Output Enable Access Time		35	ns
T <sub>BYES</sub>	UBS#, LBS# Access Time		70	ns
T <sub>BLZS</sub> <sup>1</sup>	BES# to Active Output	0		ns
T <sub>OLZS</sub> <sup>1</sup>	Output Enable to Active Output	0		ns
T <sub>BYLZS</sub> <sup>1</sup>	UBS#, LBS# to Active Output	0		ns
T <sub>BHZS</sub> <sup>1</sup>	BES# to High-Z Output		25	ns
T <sub>OHZS</sub> <sup>1</sup>	Output Disable to High-Z Output		25	ns
T <sub>BYHZS</sub> <sup>1</sup>	UBS#, LBS# to High-Z Output		35	ns
T <sub>OHS</sub>	Output Hold from Address Change	10		ns

T14.0 1335

1. This parameter is measured only for initial qualification and after a design or process change that could affect this parameter.

**TABLE 15: PSRAM Write Cycle Timing Parameters**

Symbol	Parameter	Min	Max	Units
T <sub>WCS</sub>	Write Cycle Time	70		ns
T <sub>BWS</sub>	Bank Enable to End-of-Write	60		ns
T <sub>AWS</sub>	Address Valid to End-of-Write	60		ns
T <sub>ASTS</sub>	Address Set-up Time	0		ns
T <sub>WPS</sub>	Write Pulse Width	60		ns
T <sub>WRS</sub>	Write Recovery Time	0		ns
T <sub>BYWS</sub>	UBS#, LBS# to End-of-Write	60		ns
T <sub>ODWS</sub>	Output Disable from WE# Low		30	ns
T <sub>OEWS</sub>	Output Enable from WE# High	0		ns
T <sub>DSS</sub>	Data Set-up Time	30		ns
T <sub>DHS</sub>	Data Hold from Write Time	0		ns

T15.0 1335



**TABLE 16: Flash Read Cycle Timing Parameters  $V_{DD} = 2.7-3.3V$**

Symbol	Parameter	Min	Max	Units
$T_{RC}$	Read Cycle Time	70		ns
$T_{CE}$	Chip Enable Access Time		70	ns
$T_{AA}$	Address Access Time		70	ns
$T_{OE}$	Output Enable Access Time		35	ns
$T_{CLZ}^1$	BEF# Low to Active Output	0		ns
$T_{OLZ}^1$	OE# Low to Active Output	0		ns
$T_{CHZ}^1$	BEF# High to High-Z Output		16	ns
$T_{OHZ}^1$	OE# High to High-Z Output		16	ns
$T_{OH}^1$	Output Hold from Address Change	0		ns
$T_{RP}^1$	RST# Pulse Width	500		ns
$T_{RHR}^1$	RST# High Before Read	50		ns
$T_{RY}^{1,2}$	RST# Pin Low to Read		20	$\mu s$

T16.0 1335

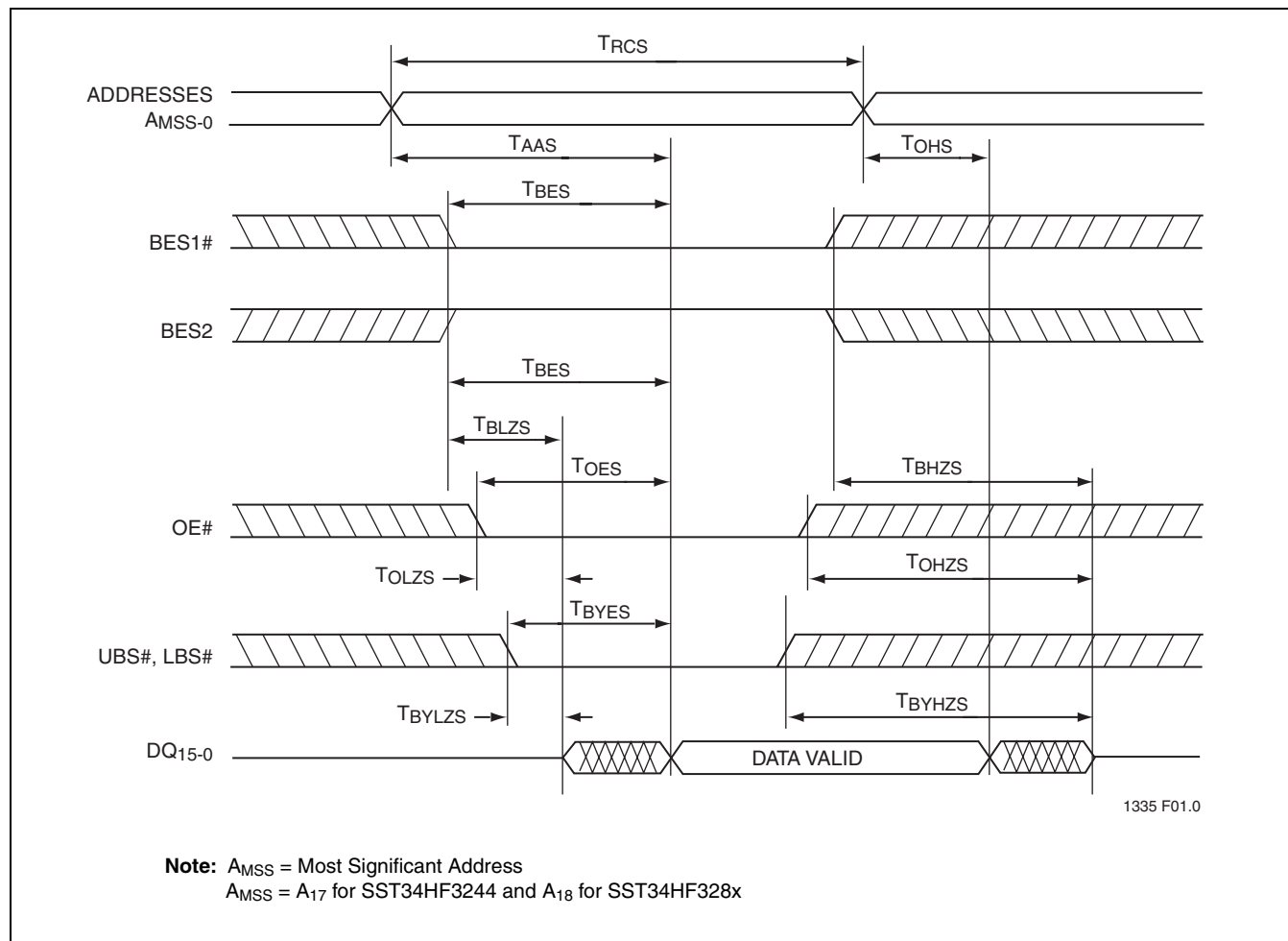
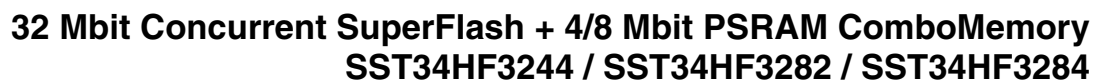
1. This parameter is measured only for initial qualification and after the design or process change that could affect this parameter.
2. This parameter applies to Sector-Erase, Block-Erase and Program operations. This parameter does not apply to Chip-Erase.

**TABLE 17: Flash Program/Erase Cycle Timing Parameters**

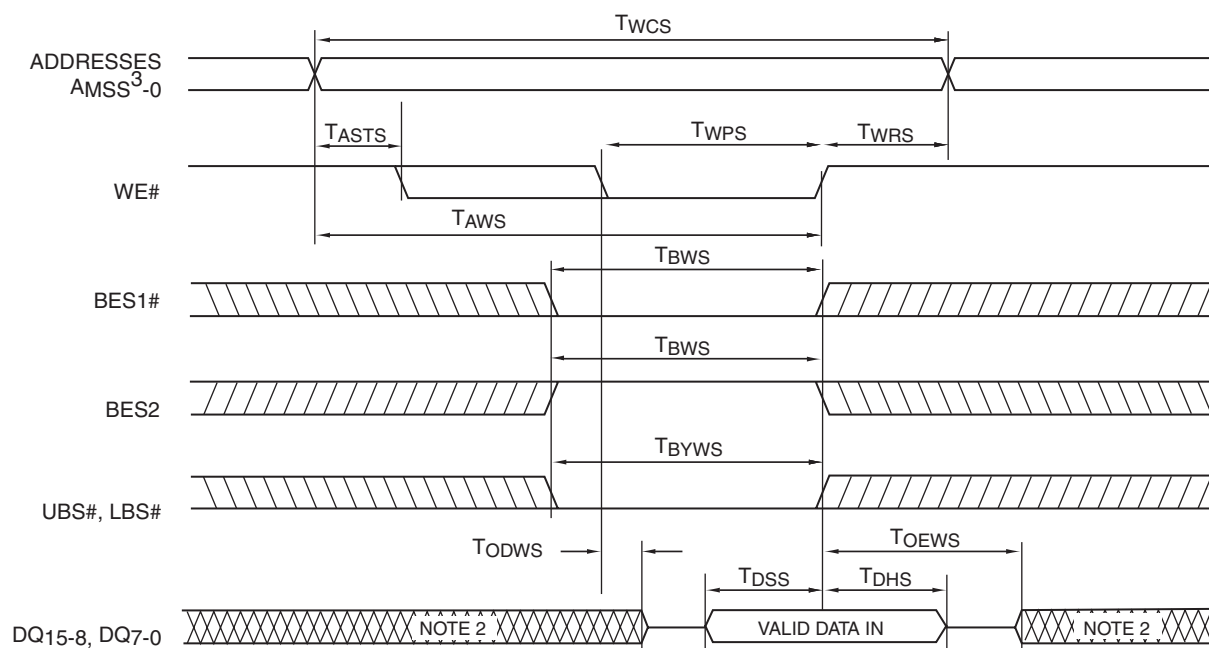
Symbol	Parameter	Min	Max	Units
$T_{BP}$	Program Time		10	$\mu s$
$T_{AS}$	Address Setup Time	0		ns
$T_{AH}$	Address Hold Time	40		ns
$T_{CS}$	WE# and BEF# Setup Time	0		ns
$T_{CH}$	WE# and BEF# Hold Time	0		ns
$T_{OES}$	OE# High Setup Time	0		ns
$T_{OEH}$	OE# High Hold Time	10		ns
$T_{CP}$	BEF# Pulse Width	40		ns
$T_{WP}$	WE# Pulse Width	40		ns
$T_{WPH}^1$	WE# Pulse Width High	30		ns
$T_{CPH}^1$	BEF# Pulse Width High	30		ns
$T_{DS}$	Data Setup Time	30		ns
$T_{DH}^1$	Data Hold Time	0		ns
$T_{IDA}^1$	Software ID Access and Exit Time		150	ns
$T_{ES}$	Erase-Suspend Latency		10	$\mu s$
$T_{BY}^{1,2}$	RY/BY# Delay Time	90		ns
$T_{BR}^1$	Bus Recovery Time		1	$\mu s$
$T_{SE}$	Sector-Erase		25	ms
$T_{BE}$	Block-Erase		25	ms
$T_{SCE}$	Chip-Erase		50	ms

T17.1 1335

1. This parameter is measured only for initial qualification and after a design or process change that could affect this parameter.
2. This parameter applies to Sector-Erase, Block-Erase, and Program operations.  
This parameter does not apply to Chip-Erase operations.



### FIGURE 4: PSRAM Read Cycle Timing Diagram



1335 F02.0

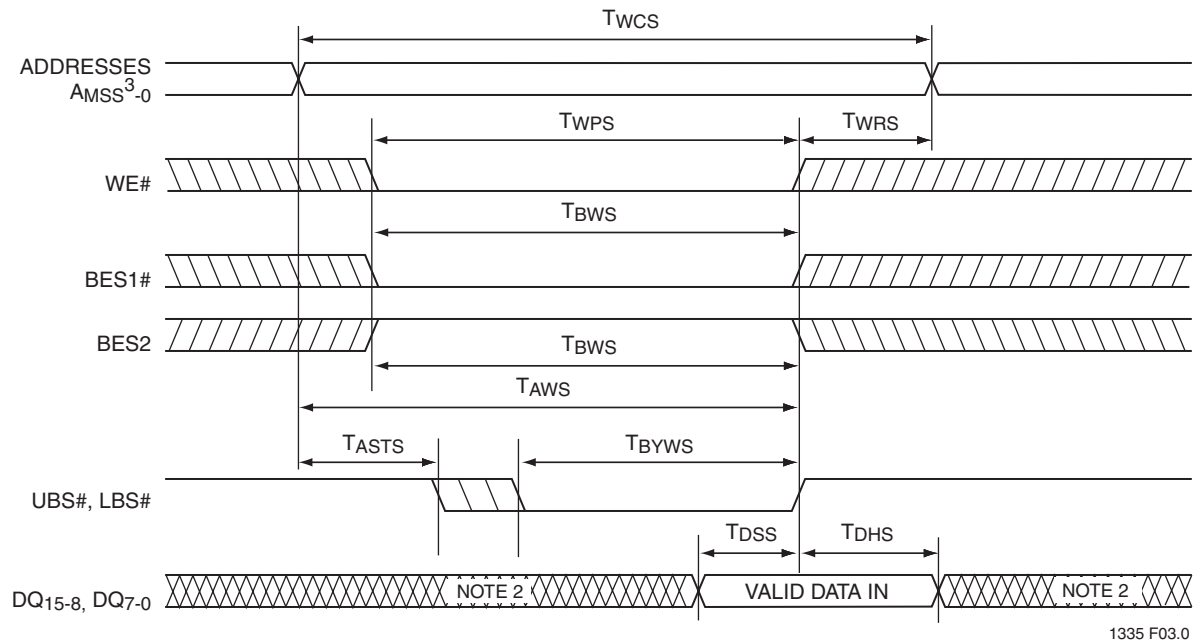
- Note:**
1. If  $\text{OE\#}$  is High during the Write cycle, the outputs will remain at high impedance.
  2. If BES1# goes Low or BES2 goes high coincident with or after  $\text{WE\#}$  goes Low, the output will remain at high impedance. If BES1# goes High or BES2 goes low coincident with or before  $\text{WE\#}$  goes High, the output will remain at high impedance. Because  $\text{D}_{\text{IN}}$  signals may be in the output state at this time, input signals of reverse polarity must not be applied.
  3.  $\text{A}_{\text{MSS}}$  = Most Significant PSRAM Address  
 $\text{A}_{\text{MSS}} = \text{A}_{17}$  for SST34HF3244 and  $\text{A}_{18}$  for SST34HF328x

**FIGURE 5: PSRAM Write Cycle Timing Diagram ( $\text{WE\#}$  Controlled)<sup>1</sup>**



# 32 Mbit Concurrent SuperFlash + 4/8 Mbit PSRAM ComboMemory SST34HF3244 / SST34HF3282 / SST34HF3284

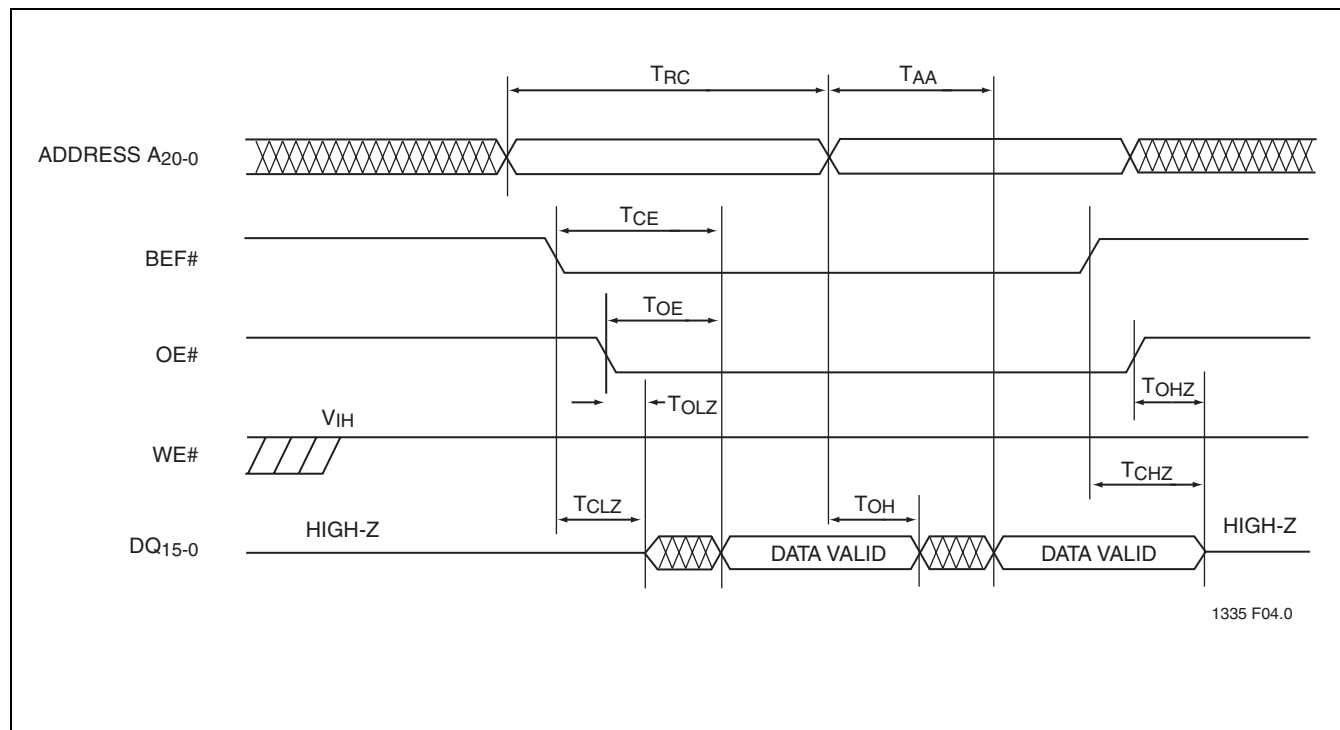
## Data Sheet



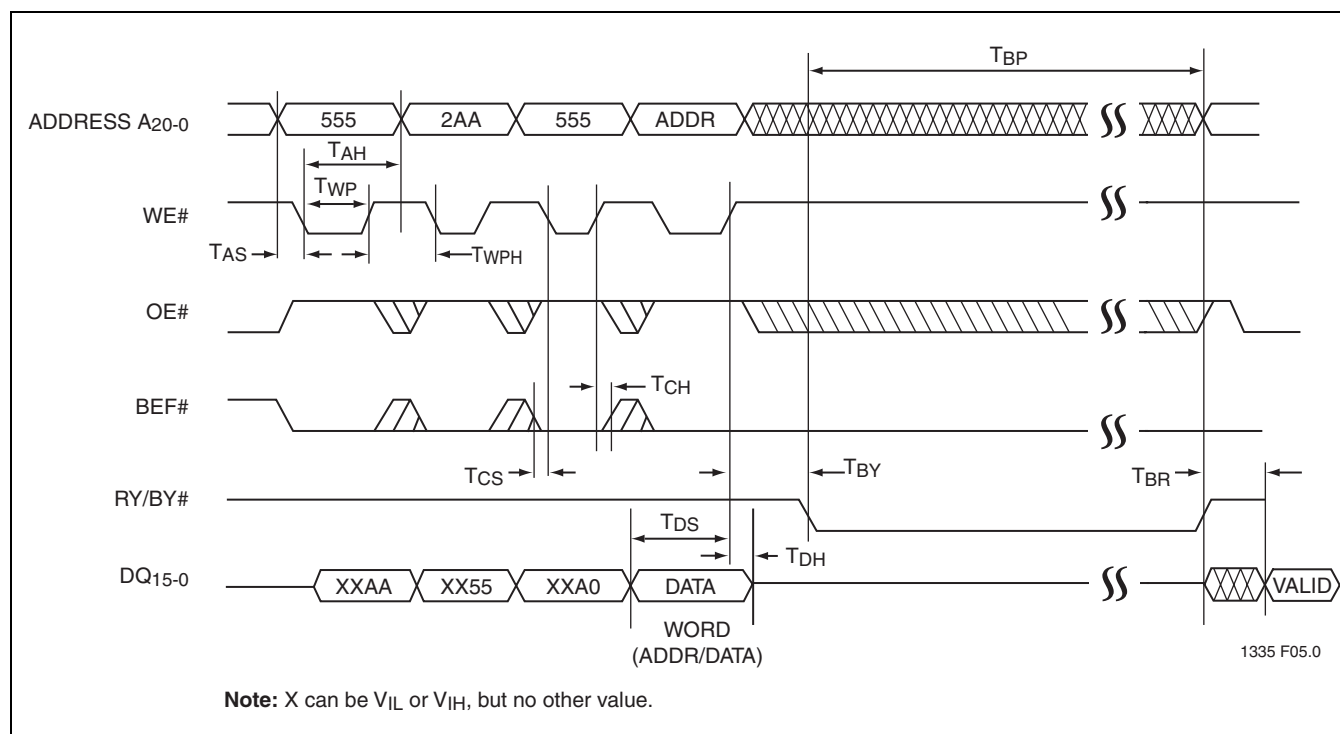
- Note:**
1. If OE# is High during the Write cycle, the outputs will remain at high impedance.
  2. Because  $D_{IN}$  signals may be in the output state at this time, input signals of reverse polarity must not be applied.
  3.  $A_{MSS}$  = Most Significant PSRAM Address  
 $A_{MSS} = A_{17}$  for SST34HF3244 and  $A_{18}$  for SST34HF328x

**FIGURE 6: PSRAM Write Cycle Timing Diagram (UBS#, LBS# Controlled)<sup>1</sup>**





**FIGURE 7: Flash Read Cycle Timing Diagram for Word Mode**  
(For Byte Mode A<sub>-1</sub> = Address Input)

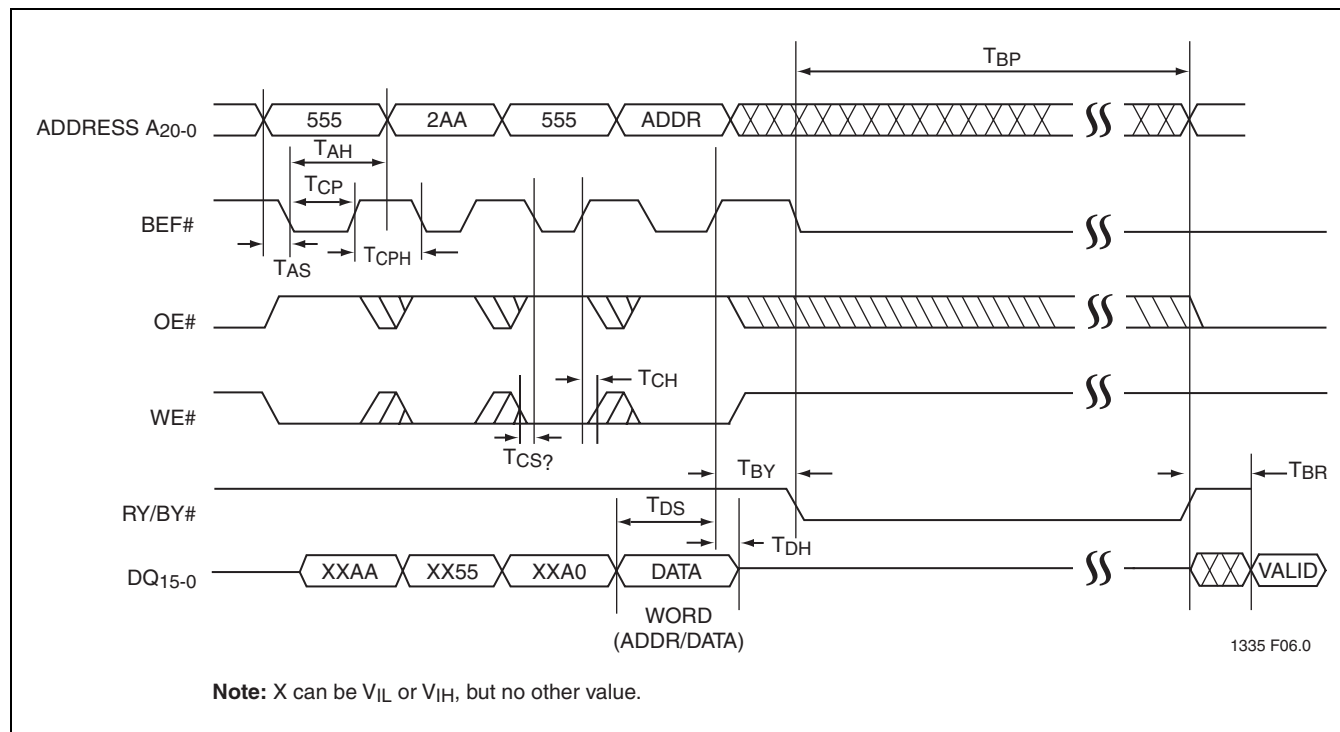


**FIGURE 8: Flash WE# Controlled Program Cycle Timing Diagram for Word Mode**  
(For Byte Mode A<sub>-1</sub> = Address Input)

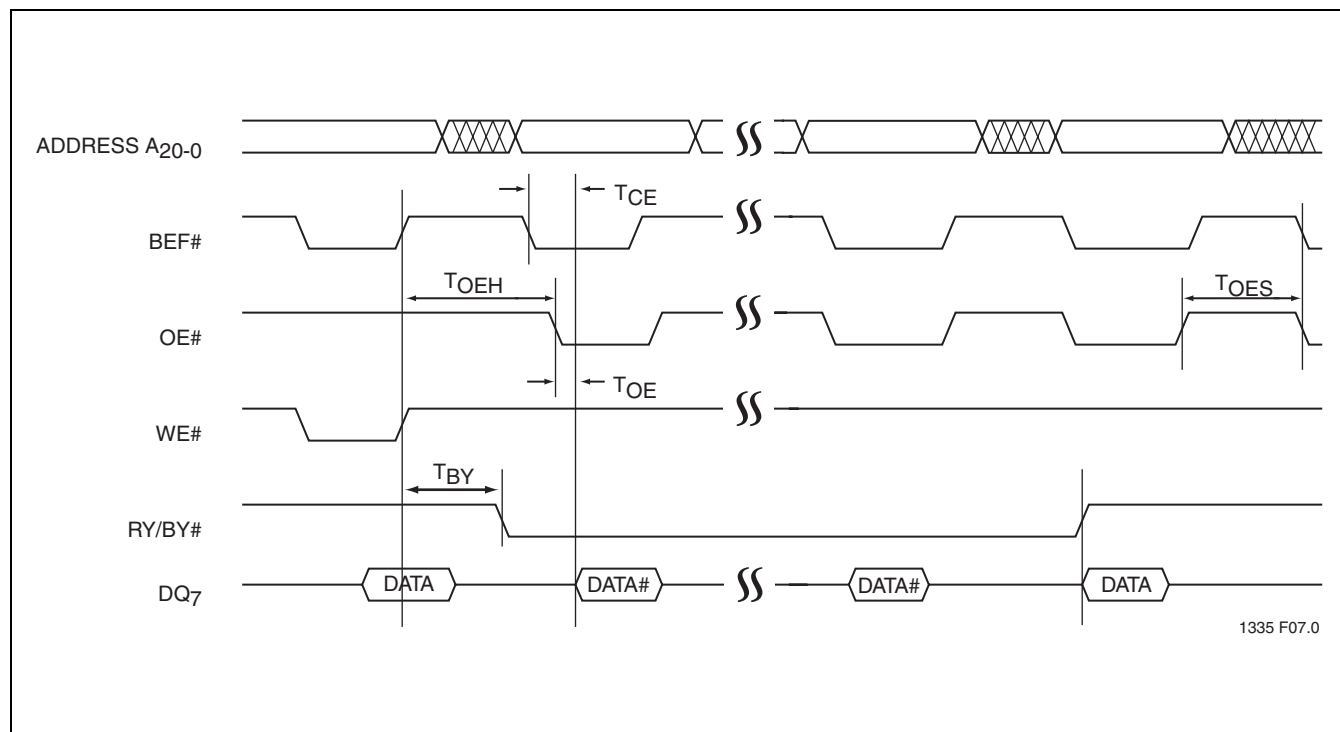


# 32 Mbit Concurrent SuperFlash + 4/8 Mbit PSRAM ComboMemory SST34HF3244 / SST34HF3282 / SST34HF3284

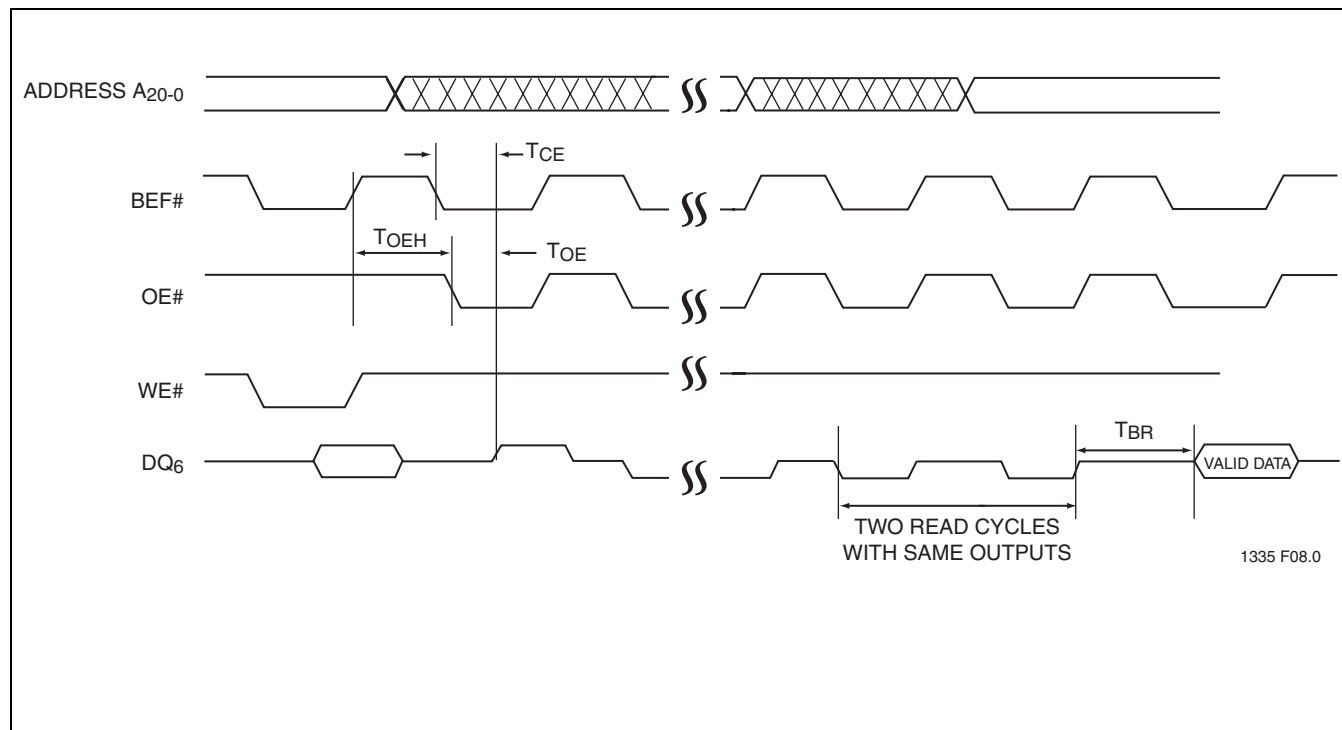
Data Sheet



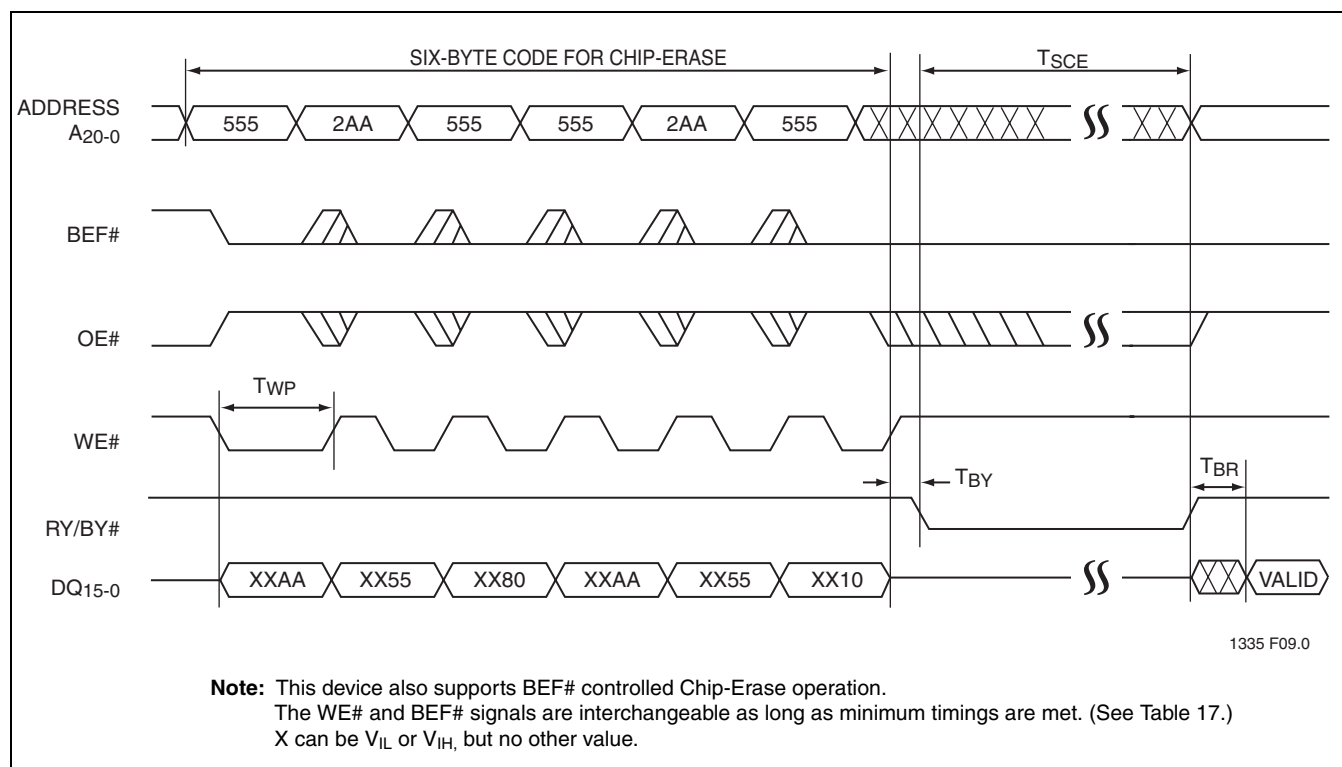
**FIGURE 9: Flash BEF# Controlled Program Cycle Timing Diagram for Word Mode  
(For Byte Mode A<sub>-1</sub> = Address Input)**



**FIGURE 10: Flash Data# Polling Timing Diagram for Word Mode  
(For Byte Mode A<sub>-1</sub> = Address Input)**



**FIGURE 11: Flash Toggle Bit Timing Diagram for Word Mode**  
(For Byte Mode A<sub>1</sub> = Don't Care)

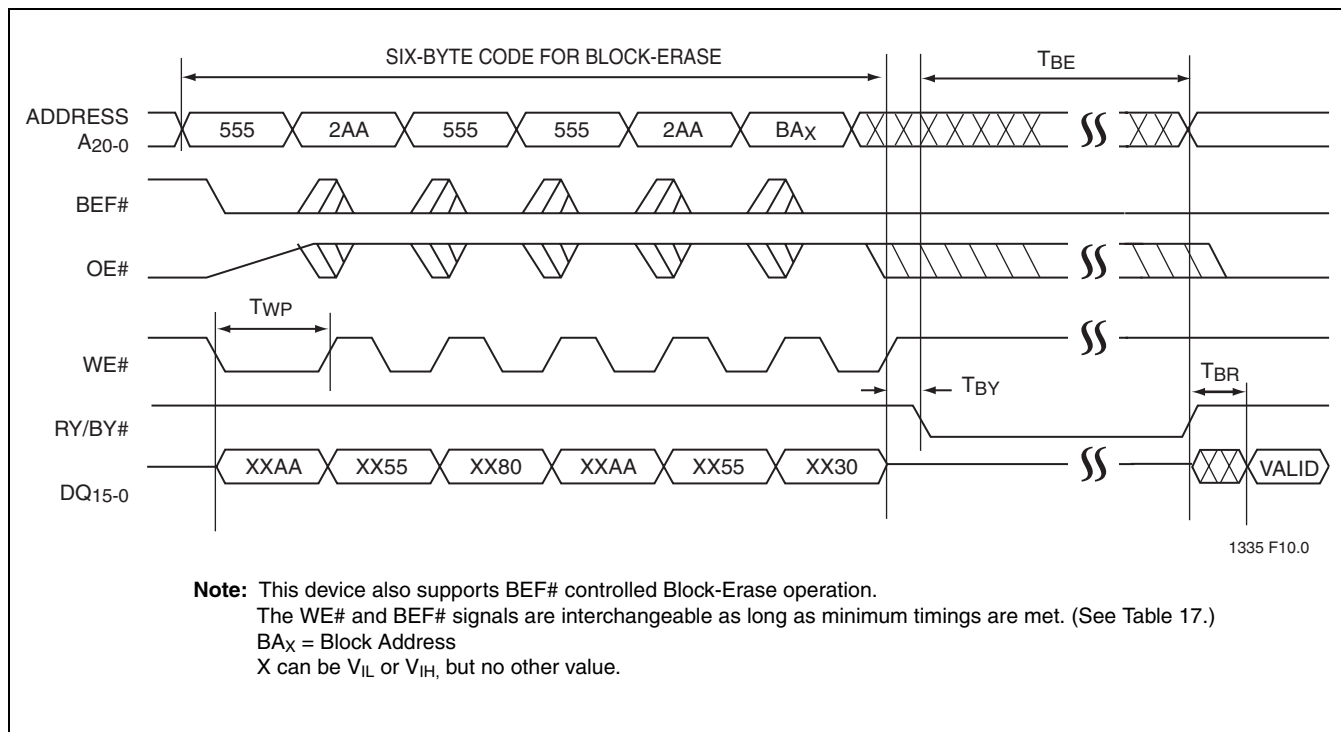


**FIGURE 12: Flash WE# Controlled Chip-Erase Timing Diagram for Word Mode**  
(For Byte Mode A<sub>1</sub> = Don't Care)

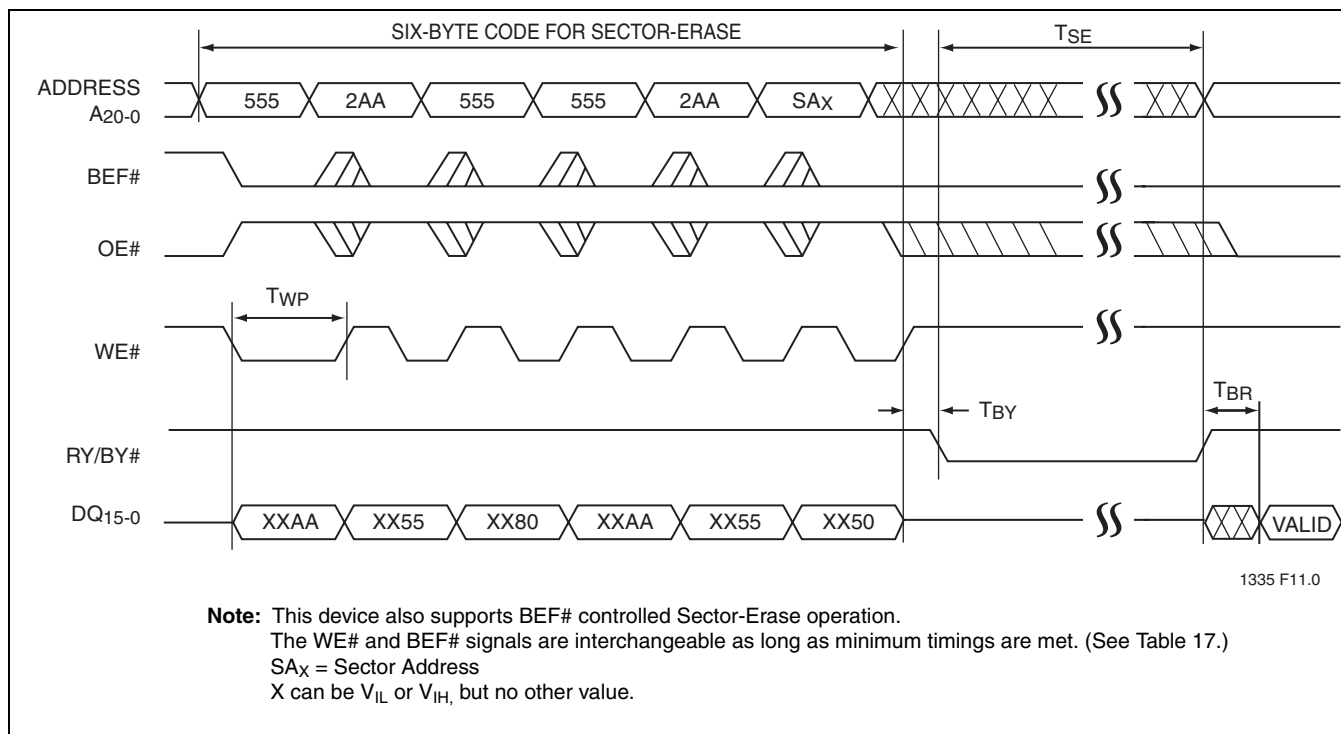


# 32 Mbit Concurrent SuperFlash + 4/8 Mbit PSRAM ComboMemory SST34HF3244 / SST34HF3282 / SST34HF3284

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**FIGURE 13: Flash WE# Controlled Block-Erase Timing Diagram for Word Mode  
(For Byte Mode A<sub>-1</sub> = Don't Care)**



**FIGURE 14: Flash WE# Controlled Sector-Erase Timing Diagram for Word Mode  
(For Byte Mode A<sub>-1</sub> = Don't Care)**

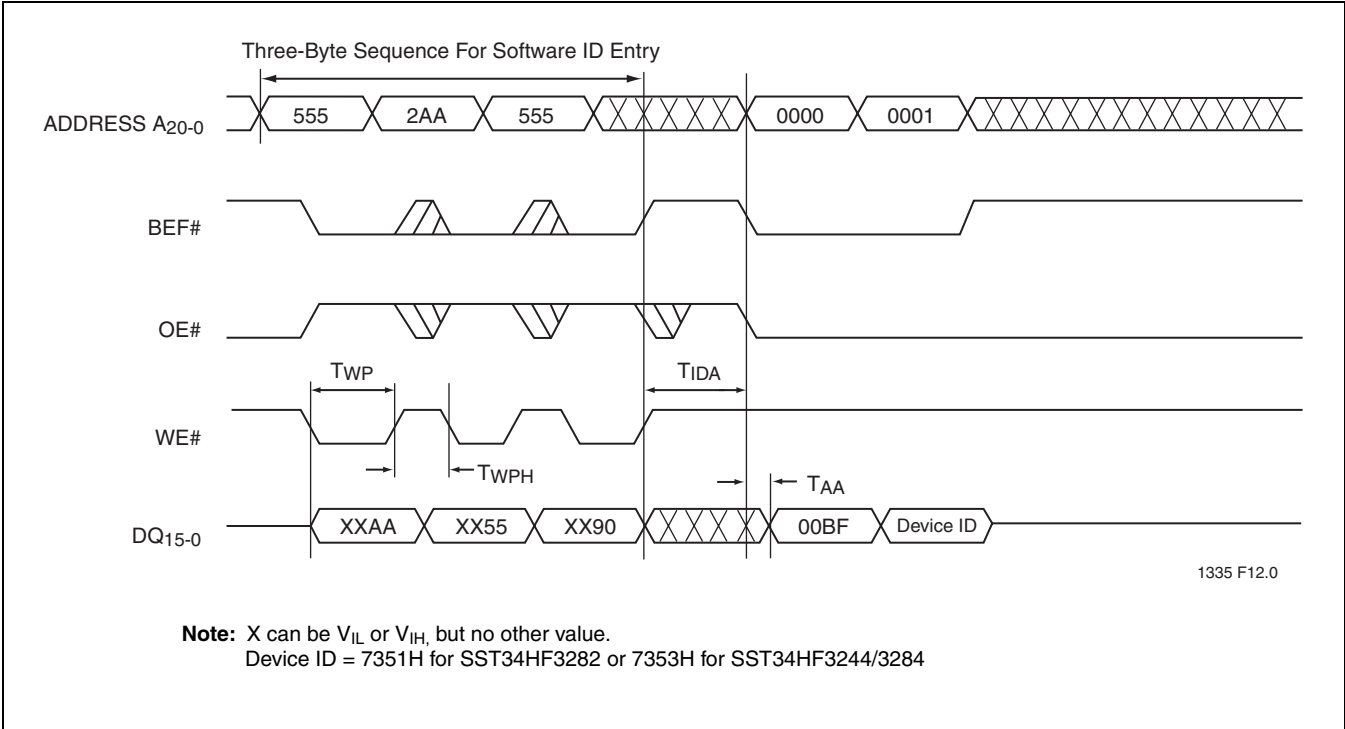


FIGURE 15: Flash Software ID Entry and Read (For Byte Mode A<sub>1</sub> = 0)

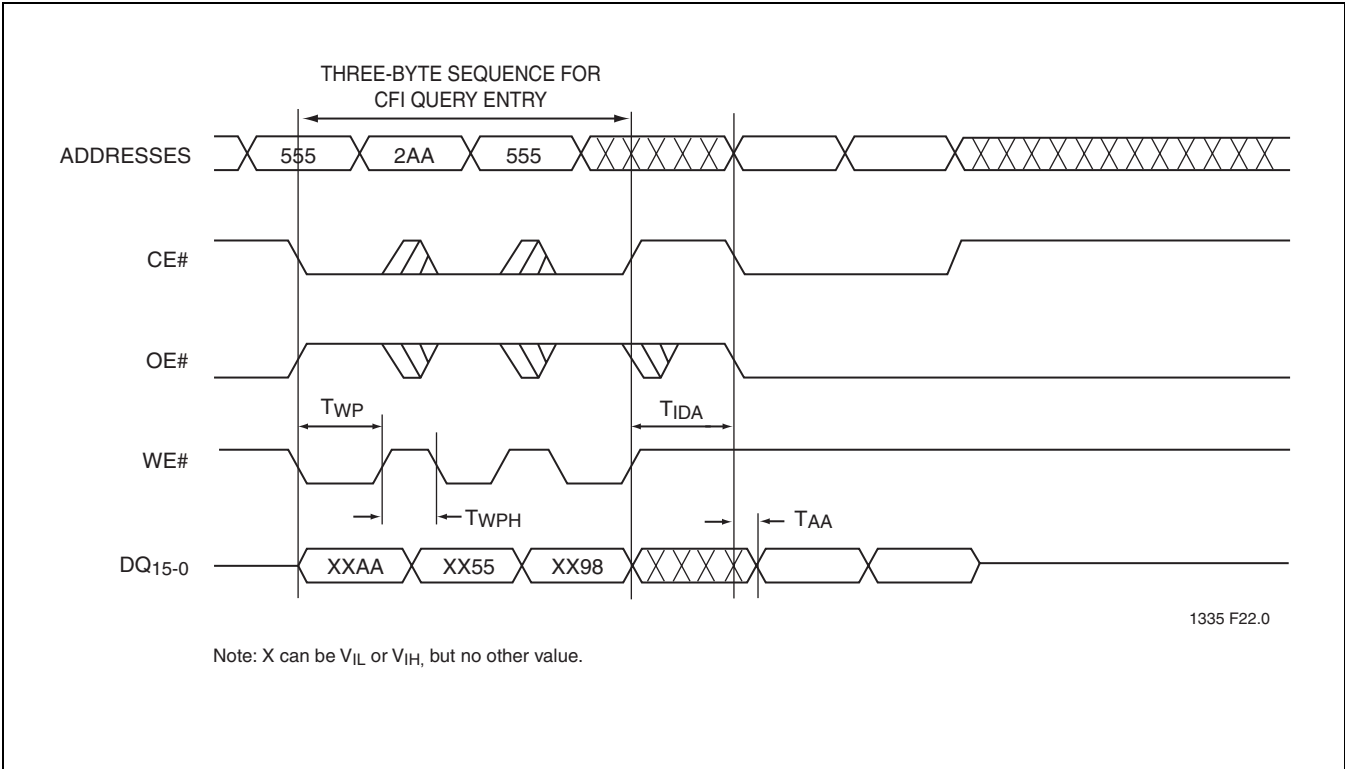


FIGURE 16: CFI Entry and Read

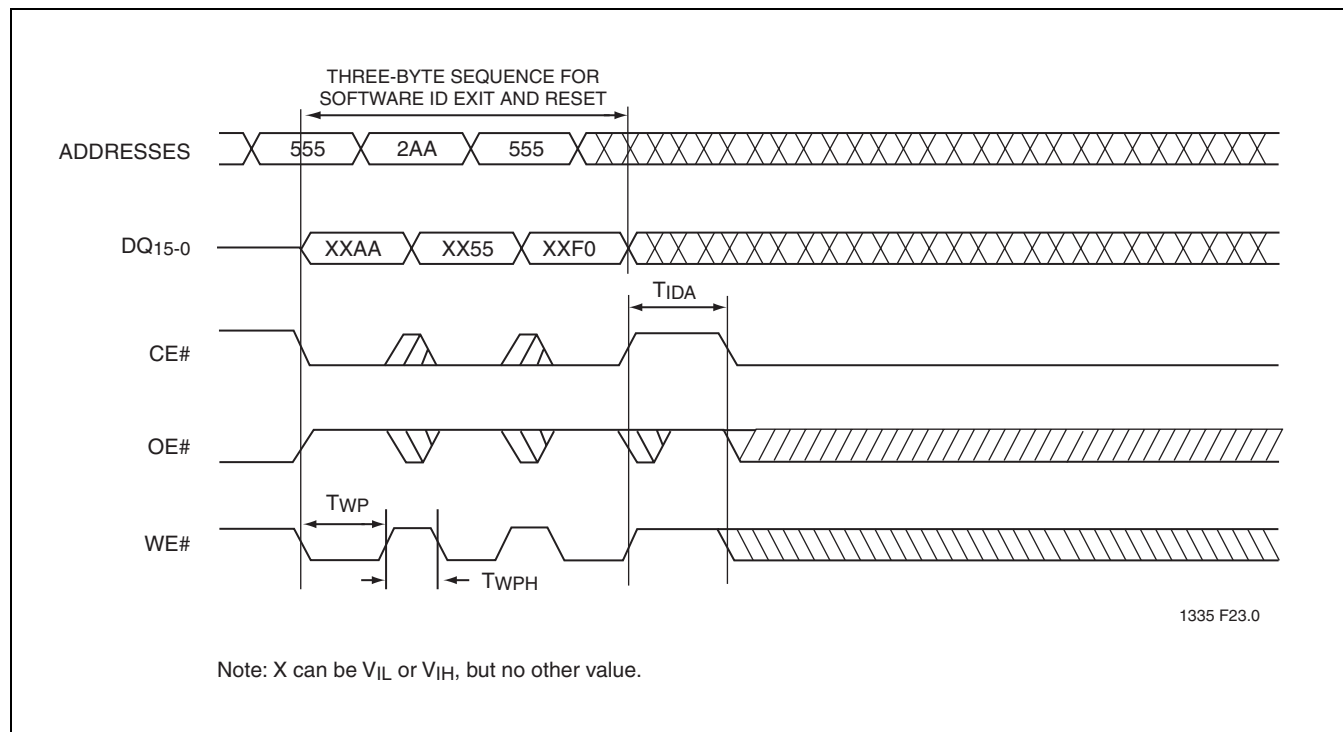


FIGURE 17: Software ID Exit/CFI Exit

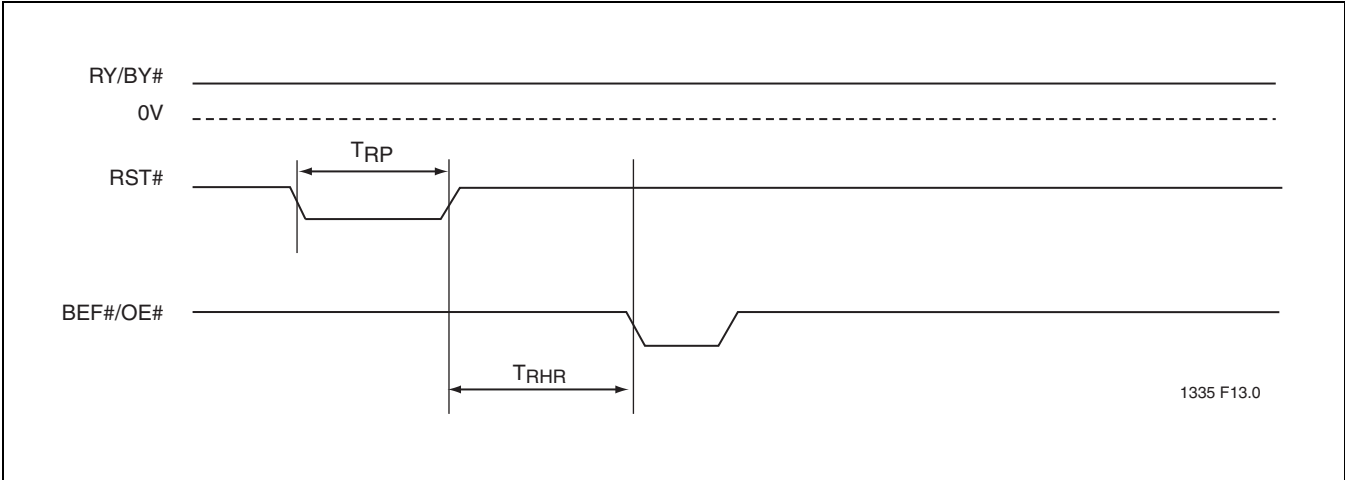


FIGURE 18: RST# Timing (when no internal operation is in progress)

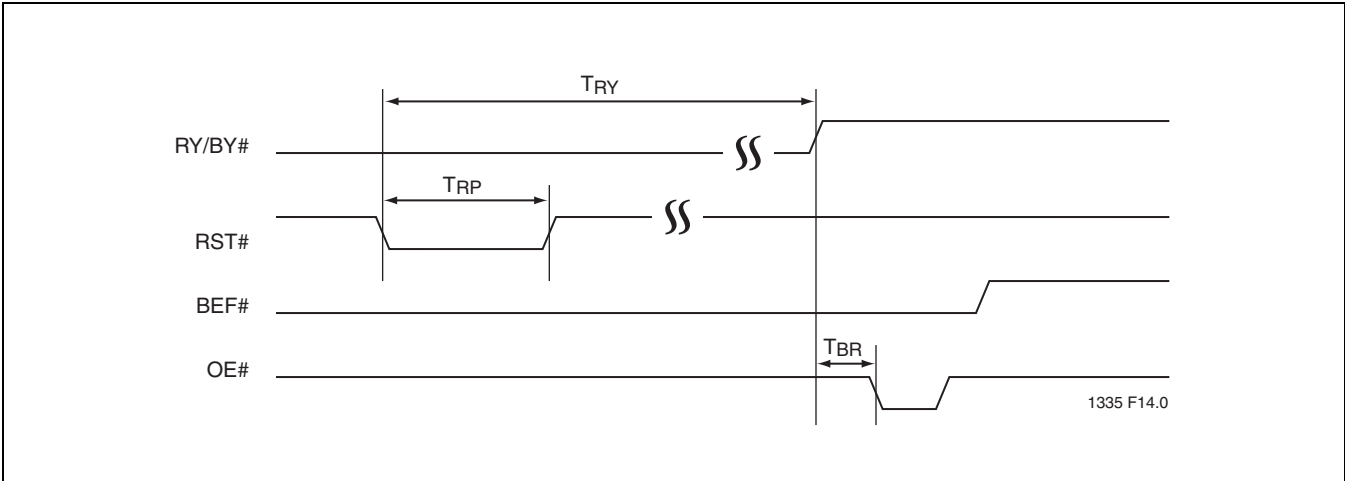


FIGURE 19: RST# Timing (during Sector- or Block-Erase operation)



# 32 Mbit Concurrent SuperFlash + 4/8 Mbit PSRAM ComboMemory SST34HF3244 / SST34HF3282 / SST34HF3284

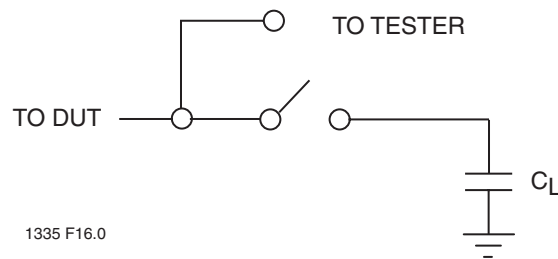
## Data Sheet



AC test inputs are driven at  $V_{IHT}$  ( $0.9 V_{DD}$ ) for a logic “1” and  $V_{ILT}$  ( $0.1 V_{DD}$ ) for a logic “0”. Measurement reference points for inputs and outputs are  $V_{IT}$  ( $0.5 V_{DD}$ ) and  $V_{OT}$  ( $0.5 V_{DD}$ ). Input rise and fall times ( $10\% \leftrightarrow 90\%$ ) are  $<5$  ns.

**Note:**  $V_{IT}$  -  $V_{INPUT}$  Test  
 $V_{OT}$  -  $V_{OUTPUT}$  Test  
 $V_{IHT}$  -  $V_{INPUT}$  HIGH Test  
 $V_{ILT}$  -  $V_{INPUT}$  LOW Test

**FIGURE 20: AC Input/Output Reference Waveforms**



**FIGURE 21: A Test Load Example**



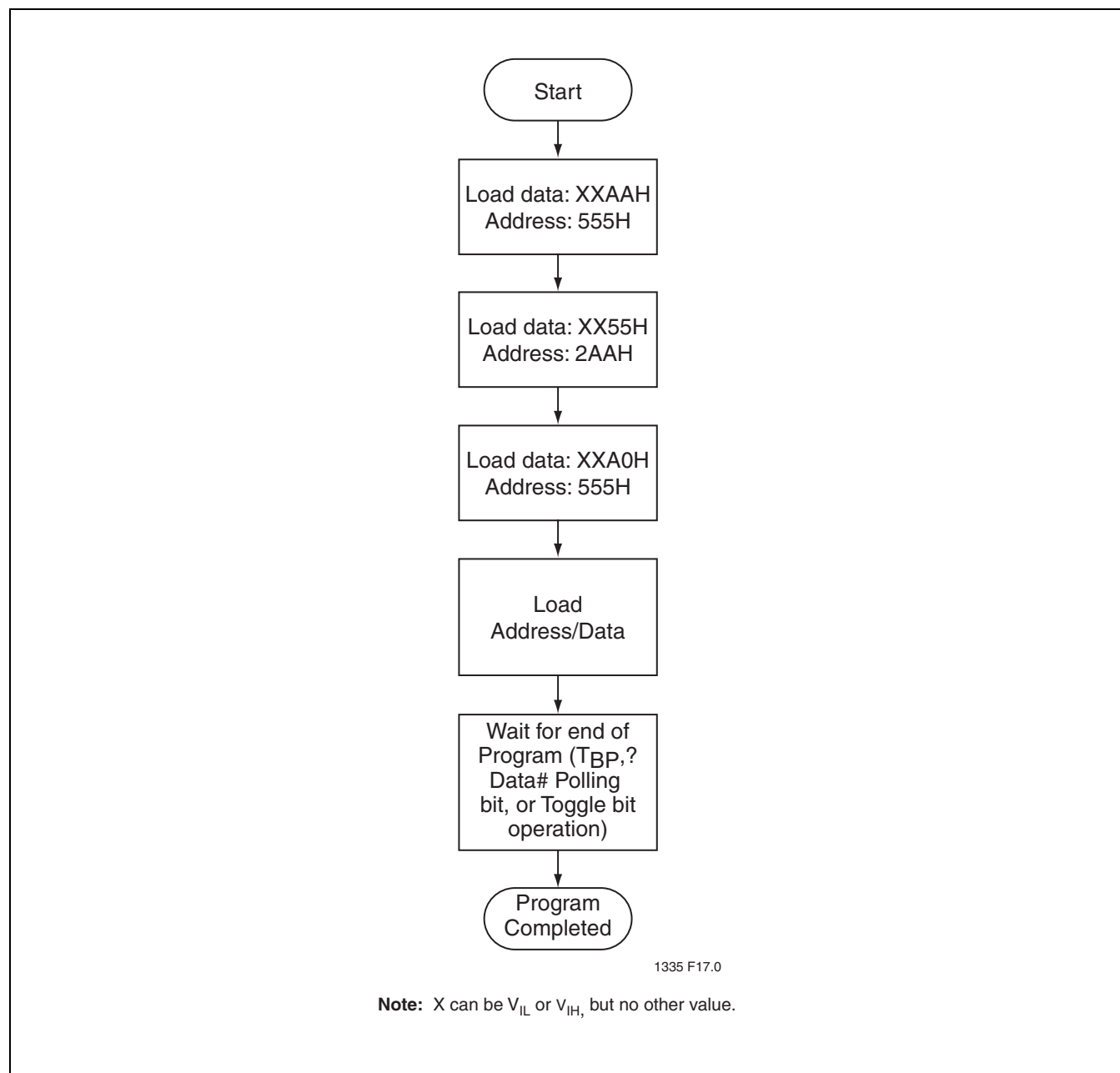


FIGURE 22: Program Algorithm

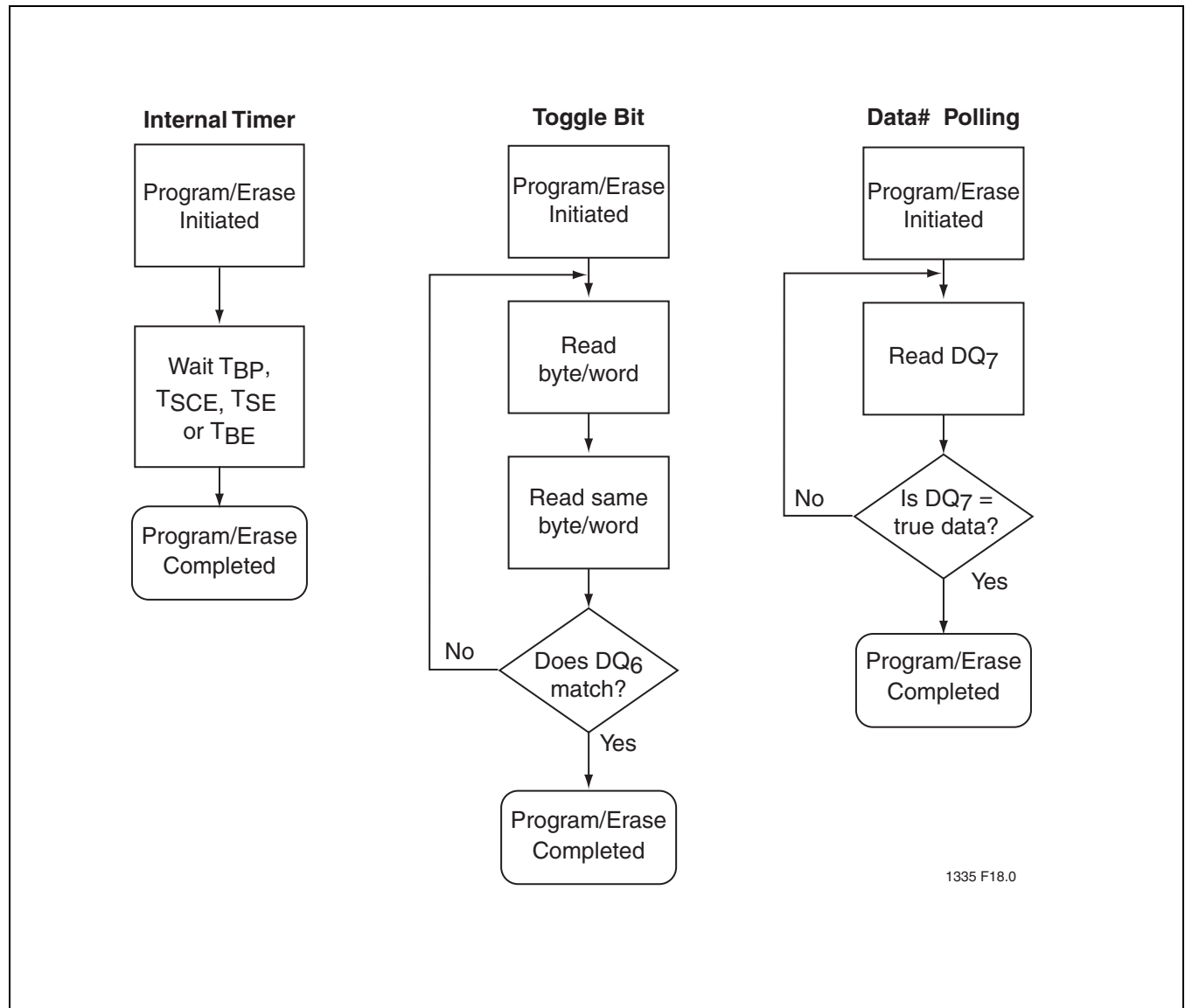


FIGURE 23: Wait Options

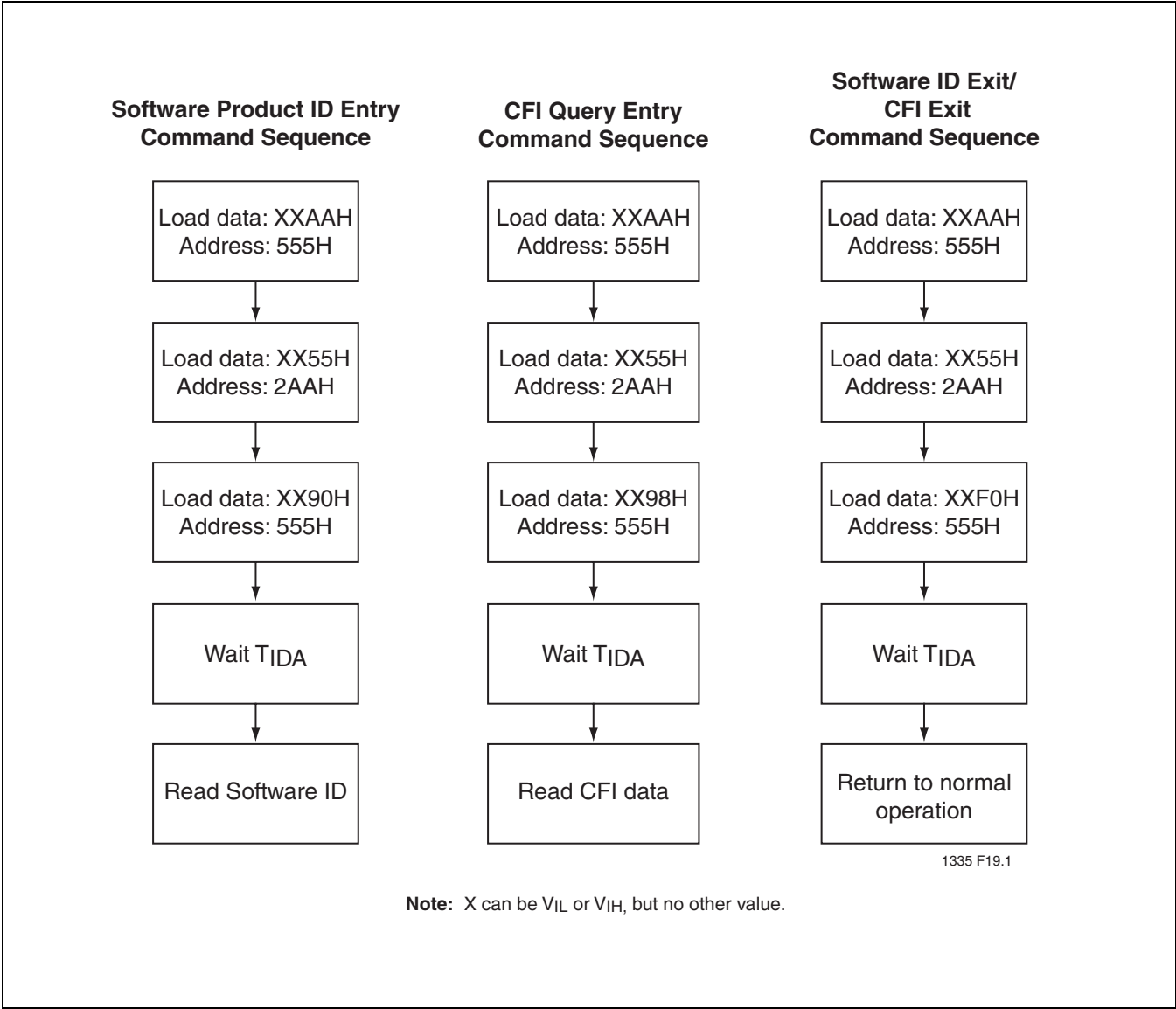


FIGURE 24: Software Product ID Command Flowcharts

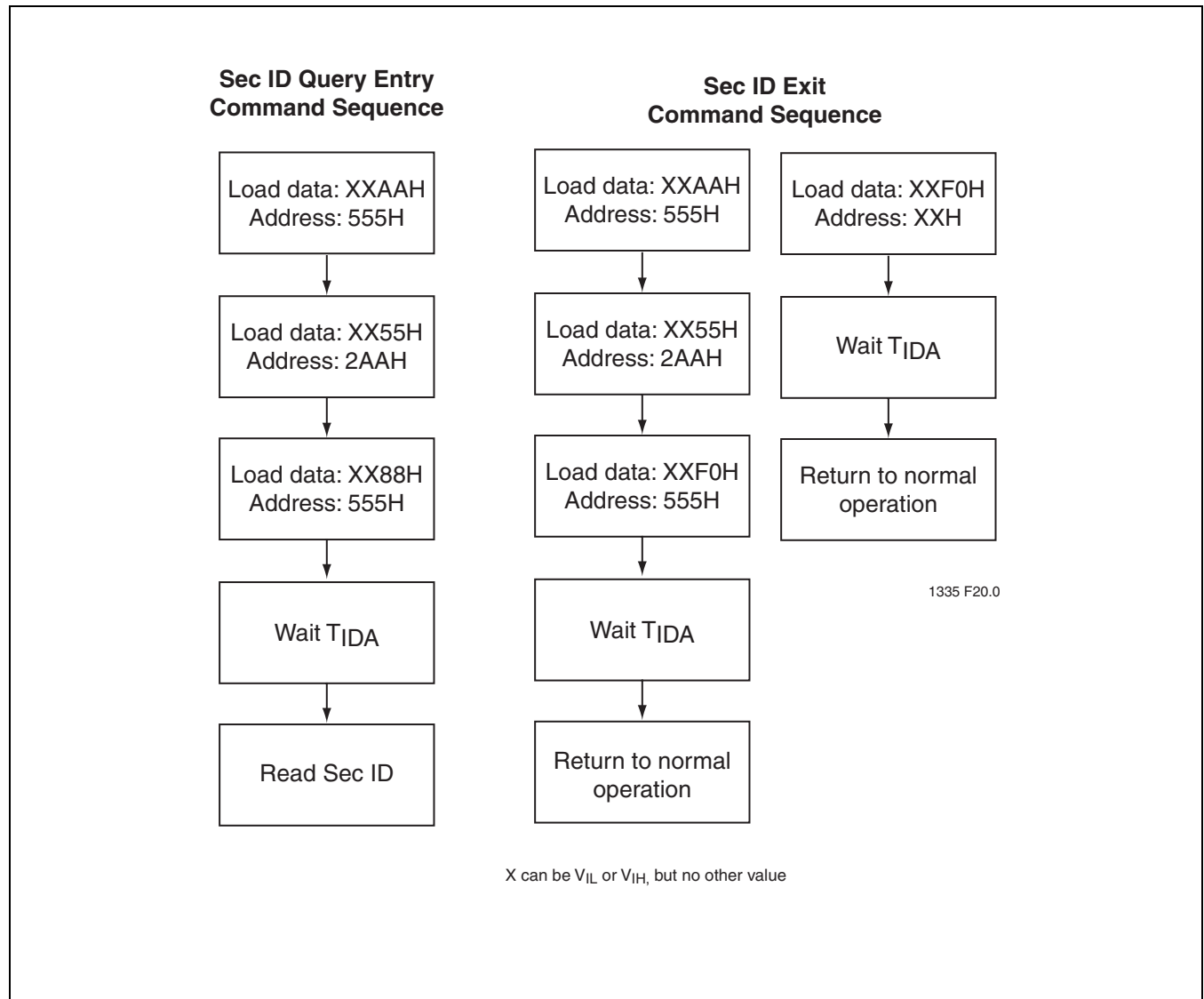


FIGURE 25: Software Sec ID Command Flowcharts

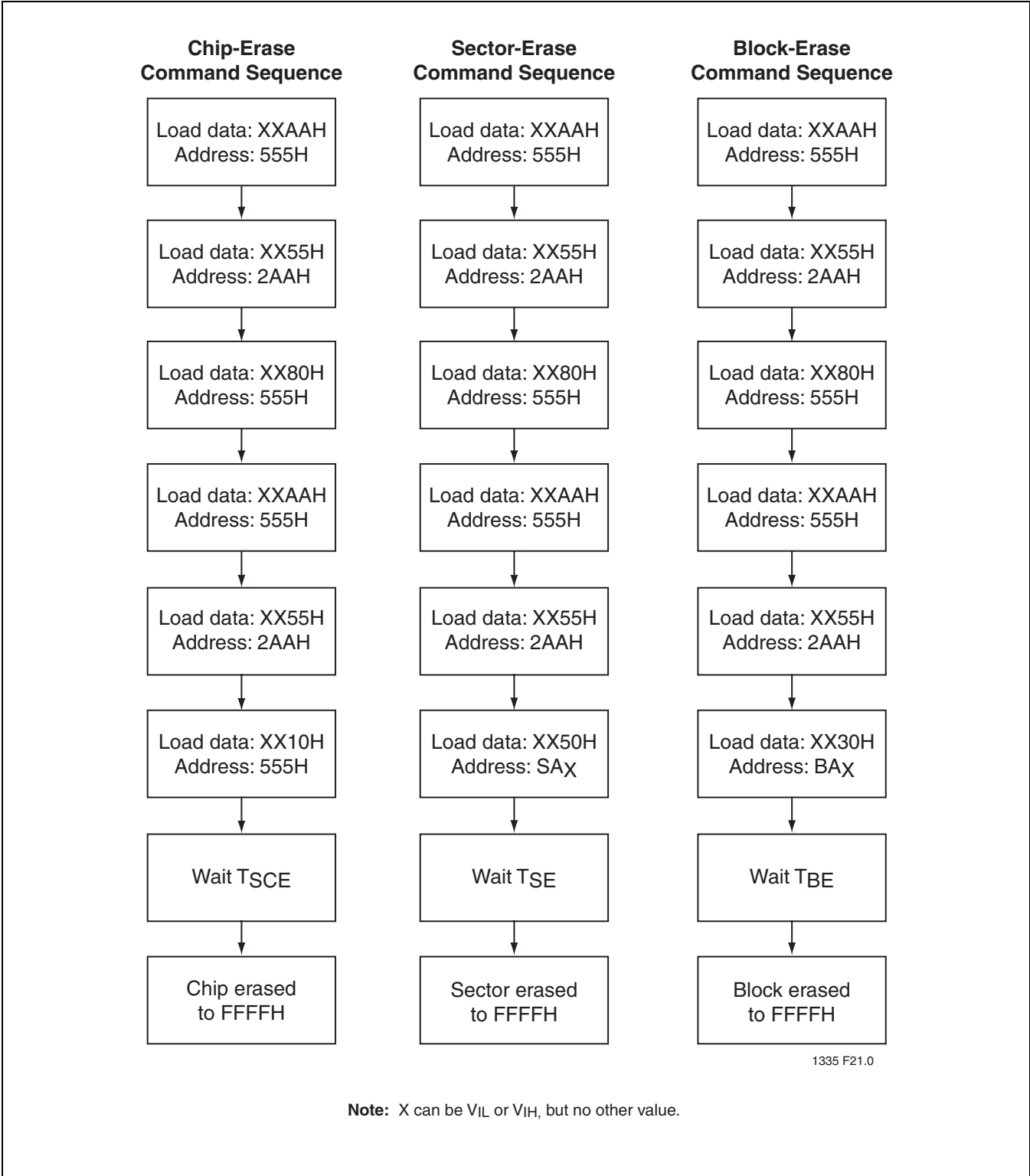


FIGURE 26: Erase Command Sequence



# 32 Mbit Concurrent SuperFlash + 4/8 Mbit PSRAM ComboMemory SST34HF3244 / SST34HF3282 / SST34HF3284

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## PRODUCT ORDERING INFORMATION

Device	Speed	Suffix1	Suffix2	
SST34HF32x4X-XXX-XX-XXXX				
				<b>Environmental Attribute</b> E <sup>1</sup> = non-Pb
				<b>Package Modifier</b> P = 56 balls S = 62 balls
				<b>Package Type</b> L1 = LFBGA (8mm x 10mm x 1.4mm, 0.45mm ball size) L = LFBGA (8mm x 10mm x 1.4mm, 0.40mm ball size)
				<b>Temperature Range</b> E = Extended = -20°C to +85°C
				<b>Minimum Endurance</b> 4 = 10,000 cycles
				<b>Read Access Speed</b> 70 = 70 ns
				<b>Version</b> blank = x16 PSRAM
				<b>Bank Split and Top Boot Block Protection</b> 2 = 4 Mbit + 28 Mbit 4 = 8 Mbit + 24 Mbit
				<b>PSRAM Density</b> 4 = 4 Mbit 8 = 8 Mbit
				<b>Flash Density</b> 32 = 32 Mbit
				<b>Voltage</b> H = 2.7-3.3V
				<b>Product Series</b> 34 = Concurrent SuperFlash + PSRAM ComboMemory

1. Environmental suffix "E" denotes non-Pb solder.  
SST non-Pb solder devices are "RoHS Compliant".

## 32 Mbit Concurrent SuperFlash + 4/8 Mbit PSRAM ComboMemory SST34HF3244 / SST34HF3282 / SST34HF3284



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### Valid combinations for SST34HF3244

SST34HF3244-70-4E-L1PE      SST34HF3244-70-4E-LSE

### Valid combinations for SST34HF3282

SST34HF3282-70-4E-L1PE      SST34HF3282-70-4E-LSE

### Valid combinations for SST34HF3284

SST34HF3284-70-4E-L1PE      SST34HF3284-70-4E-LSE

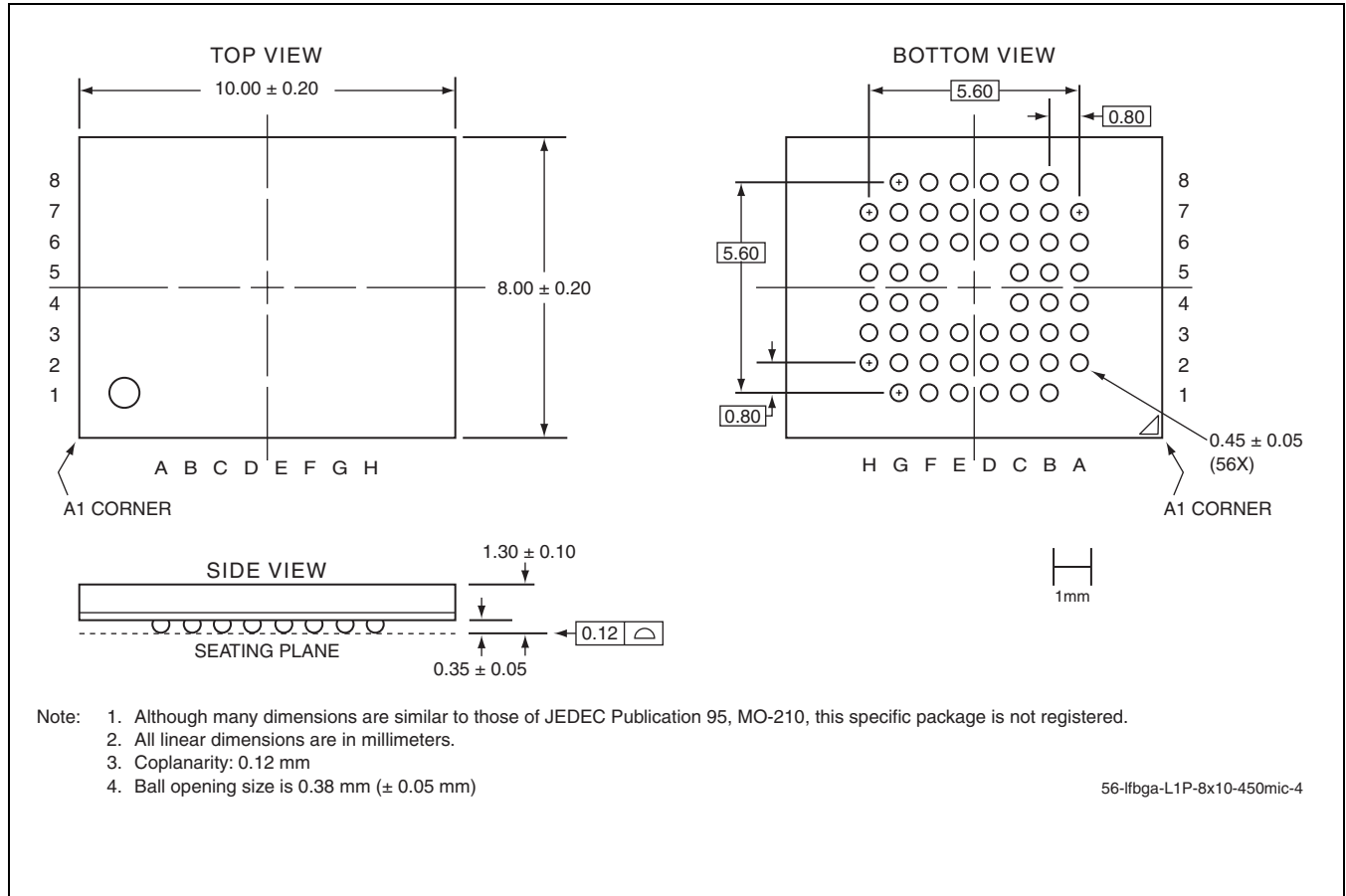
**Note:** Valid combinations are those products in mass production or will be in mass production. Consult your SST sales representative to confirm availability of valid combinations and to determine availability of new combinations.



# 32 Mbit Concurrent SuperFlash + 4/8 Mbit PSRAM ComboMemory SST34HF3244 / SST34HF3282 / SST34HF3284

Data Sheet

## PACKAGING DIAGRAMS



**FIGURE 27: 56-ball Low-profile, Fine-pitch Ball Grid Array (LFBGA) 8mm x 10mm  
SST Package Code: L1P**



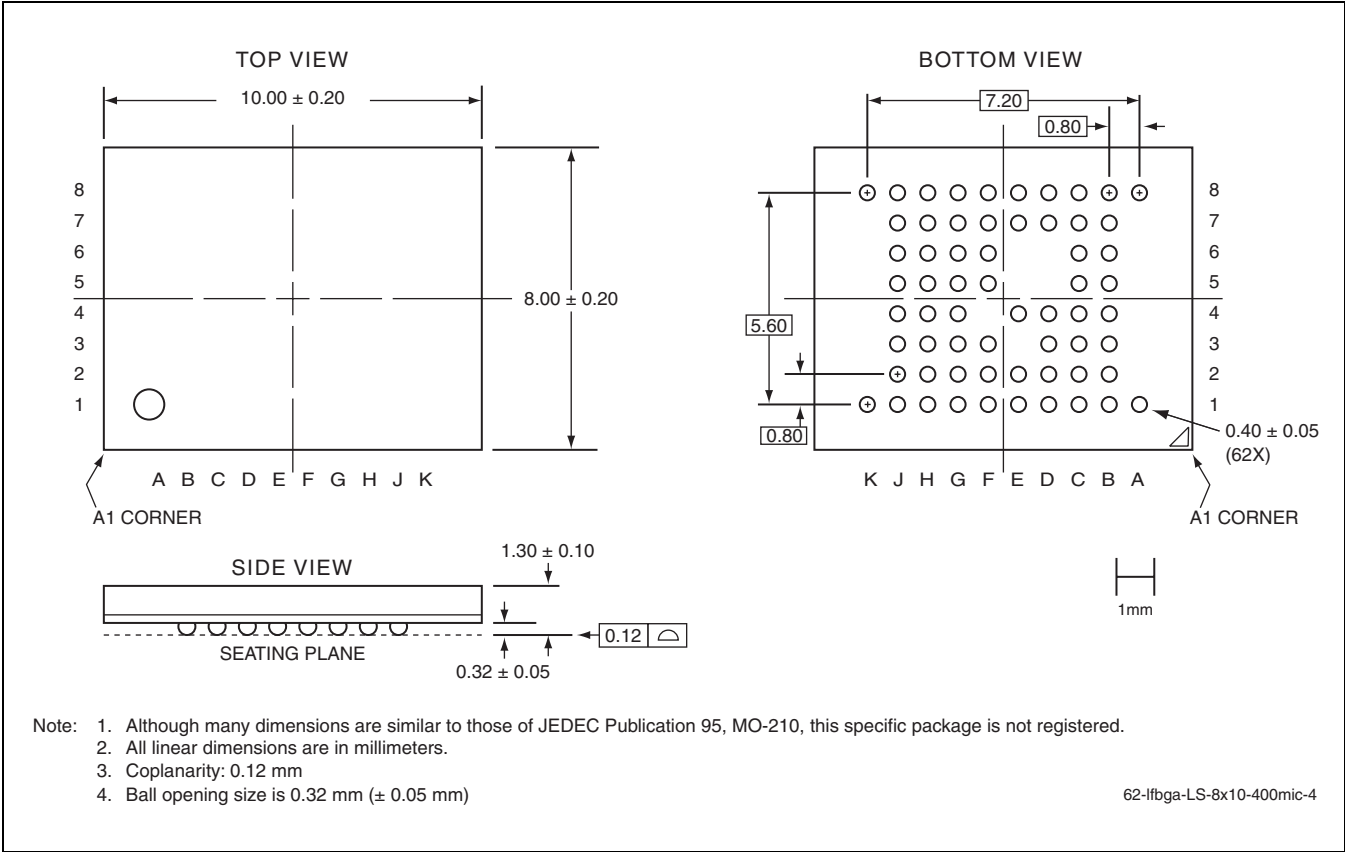


FIGURE 28: 62-ball Low-profile, Fine-pitch Ball Grid Array (LFBGA) 8mm x 10mm  
SST Package Code: LS

TABLE 18: Revision History

Number	Description	Date
00	• Initial Release	Aug 2006